ELSEVIER

Ultramicroscopy 60 (1995) 445–464

ultramicroscopy

Author index to volumes 51–60

Abstreiter, G., see Kolb 57 (1995) 208
Agraït, N., see Vélez 60 (1995) 41
Alarco, J.A., E. Olsson, Z.G. Ivanov, P.Å. Nilsson, D. Winkler, E.A. Stepantsov and A.Ya. Tzalenchuk, Microstructure of an artificial grain boundary weak link in an $YBa_2Cu_3O_{7-\delta}$ thin film grown on a (100)(110), [001]-tilt $Y-ZrO_2$ bicrystal 51 (1993) 239
Albarède, P.H., see Ayache 60 (1995) 195
Allard, L., see Joy 51 (1993) 1
Allard, L., see Zhang 51 (1993) 21
Allard, L.F., see Völkl 58 (1995) 97
Allen, C.W., In situ ion- and electron-irradiation effects studies in transmission electron microscopes 56 (1994) 200
Allen, E.V., see Dunn 57 (1995) 113
Allen, L.J., T.W. Josefsson and C.J. Rossouw, Interaction delocalization in characteristic X-ray emission from light elements 55 (1994) 258
Allen, L.J., see Spargo 55 (1994) 329
Amelinckx, S., O. Milat and G. Van Tendeloo, Selective imaging of sublattices in complex structures 51 (1993) 90
Amelinckx, S., see Van Tendeloo 51 (1993) 168
Amelinckx, S., see Zhang 54 (1994) 237
Amelinckx, S., see Zhang 55 (1994) 25
Anderson, G.A., see Dunn 57 (1995) 113
Anderson, S.C., see Chou 55 (1994) 334
Anderson, S.L., see Ramachandran 51 (1993) 282
Andersson, T.G., see Olsson 51 (1993) 215
Ando, T., Y. Taniguchi, Y. Takai, Y. Kimura, R. Shimizu and T. Ikuta, Development of real-time defocus-modulation-type active image processing (DMAIP) for spherical-aberration-free TEM observation 54 (1994) 261
Anstis, G.R., G.J. Auchterlonie and J.C. Barry, Analysis of power spectra of high resolution electron micrographs 52 (1993) 167
Aoyama, K., see Ru 55 (1994) 209
Aoyama, K., K. Ogawa, Y. Kimura and Y. Fujiyoshi, A method for 2D crystallization of soluble proteins at liquid–liquid interface 57 (1995) 345
Ashenford, D.A., see Hutchison 53 (1994) 91
Ataka, T., see Fujihira 57 (1995) 118
Ataka, T., see Muramatsu 57 (1995) 141
Ataka, T., see Fujihira 57 (1995) 176
Atici, Y. and D. Cherns, Observation of crystal distortions in SiGe/Si superlattice using a new application of large-angle convergent-beam electron diffraction 58 (1995) 435
Auchterlonie, G.J., see Anstis 52 (1993) 167
Awaji, M., see Sukedai 54 (1994) 192
Ayache, J. and P.H. Albarède, Application of the ionless tripod polisher to the preparation of YBCO superconducting multilayer and bulk ceramics thin films 60 (1995) 195

Baba, T., see Horita 58 (1995) 327
Baba-Kishi, K.Z., Shadow imaging of surface topography in a conventional scanning electron microscope by forward scattered electrons 54 (1994) 1
Bachelot, R., see Gleyzes 57 (1995) 318
Bacher, A., see Rübenkamm 58 (1995) 337
Bachmann, L., see Rübenkamm 58 (1995) 337
Balasubramaniam, S., see Cloninger 57 (1995) 223
Bange, K., see Becker 52 (1993) 73
Bangert, H., see Schattschneider 53 (1994) 181
Banhart, F., Strains in crystals with amorphous surface films studied by convergent beam electron diffraction and high-resolution imaging 56 (1994) 233
Barber, D.J., Radiation damage in ion-milled specimens: characteristics, effects and methods of damage limitation 52 (1993) 101
Barchiesi, D. and D. Van Labeke, A perturbative diffraction theory of a multilayer system: applications to near-field optical microscopy SNOM and STOM 57 (1995) 196
Barkshire, I.R., see Kenny 56 (1994) 289
Barkshire, I.R., see Prutton 59 (1995) 47
Barreteau, C. and F. Ducastelle, The orthogonalized plane-wave method applied to the calculation of dynamical effects in electron diffraction 57 (1995) 11
Barry, J.C., see Anstis 52 (1993) 167
Barry, J.C., A study of nickel sulphide stones in tempered glass 52 (1993) 297
Bartsch, M., see Messerschmidt 56 (1994) 163

Elsevier Science B.V.

Batson, P.E., Conduction bandstructure in strained silicon by spatially resolved electron energy loss spectroscopy 59 (1995) 63
Bauer, S., A. Rosenauer, P. Link, W. Kuhn, J. Zweck and W. Gebhardt, Misfit dislocations in epitaxial ZnTe/GaAs (001) studied by HRTEM 51 (1993) 221
Baumann, F.H., see Kisielowski 58 (1995) 131
Baumeister, W., see Rübenkamm 58 (1995) 337
Bayle, P., T. Deutsch, B. Gilles, F. Lançon, A. Marty and J. Thibault, Quantitative analysis of the deformation and chemical profiles of strained multilayers 56 (1994) 94
Becker, O. and K. Bange, Ultramicrotomy: an alternative cross section preparation for oxidic thin films on glass 52 (1993) 73
Beeching, M.J. and A.E.C. Spargo, A method for crystal potential retrieval in HRTEM 52 (1993) 243
Beeching, M.J., see Spargo 55 (1994) 329
Behal, S.K., see Hunt 58 (1995) 55
Belmont, A., see Delaney 56 (1994) 319
Bentley, J., see Wang 51 (1993) 64
Berger, A., J. Mayer and H. Kohl, Detection limits in elemental distribution images produced by energy filtering TEM: case study of grain boundaries in Si_3N_4 55 (1994) 101
Berger, A., see Kohl 59 (1995) 191
Berger, A., see Dinges 60 (1995) 49
Berger, S.D., see Eaglesham 53 (1994) 319
Bernaerts, D., see Zhang 55 (1994) 25
Berriman, J. and N. Unwin, Analysis of transient structures by cryo-microscopy combined with rapid mixing of spray droplets 56 (1994) 241
Beveridge, T.J., see Firtel 55 (1994) 113
Bierwolf, R. and M. Hohenstein, Premise-free reconstruction of the exit-surface wave function in HRTEM 56 (1994) 32
Binks, C.J., see Williamson 57 (1995) 235
Bird, D.M., see Saunders 60 (1995) 311
Bithell, E.G., R.C. Doole and M.J. Goringe, On the extraction of high quality data from real-time transmission electron microscopy experiments 56 (1994) 172
Blackford, B., see Firtel 55 (1994) 113
Blanche, G., see Hug 59 (1995) 121
Bleloch, A.L., see Ito 52 (1993) 347
Bleloch, A.L., see Müllejans 52 (1993) 360
Bleloch, A.L., M.R. Castell, A. Howie and C.A. Walsh, Atomic and electronic Z-contrast effects in high-resolution imaging 54 (1994) 107
Bleloch, A.L., see Tomita 54 (1994) 125
Block, J.H., see Medvedev 53 (1994) 27
Boccara, A.C., see Gleyzes 57 (1995) 318
Böhm, G., see Kolb 57 (1995) 208
Bölger, B., see Moers 57 (1995) 298
Bolton, J.P.R. and M. Chen, Electron energy loss in multilayered slabs 60 (1995) 247
Bonnet, N., Preliminary investigation of two methods for the automatic handling of multivariate maps in microanalysis 57 (1995) 17
Bonnet, N., Erratum to "Preliminary investigation of two methods for the automatic handling of multivariate maps in microanalysis" [Ultramicroscopy 57 (1995) 17–27] 58 (1995) 441
Bonnet, N., M. Herbin and P. Vautrot, Extension of the scatterplot approach to multiple images 60 (1995) 349
Bonnet, R., see Loubradou 51 (1993) 270
Booker, G.R., see Konkol 55 (1994) 183
Booker, G.R., see Konkol 58 (1995) 233
Boothroyd, C.B. and C.J. Humphreys, Measuring the height of steps on MgO cubes using Fresnel contrast in a scanning transmission electron microscope 52 (1993) 318
Boothroyd, C.B., see Cullen 56 (1994) 127
Boothroyd, C.B., see Botton 59 (1995) 93
Boothroyd, C.B., see Meyer 59 (1995) 283
Boseck, S., see Höper 60 (1995) 17
Böttcher, B., Electron cryo-microscopy of graphite in amorphous ice 58 (1995) 417
Botton, G.A., see Burgess 55 (1994) 276
Botton, G.A., C.B. Boothroyd and W.M. Stobbs, Momentum dependent energy loss near edge structures using a CTEM: the reliability of the methods available 59 (1995) 93
Boudet, A., see Tournier-Lasserve 58 (1995) 123
Boudreau, B.D., see Cloninger 57 (1995) 223
Boulin, C., see Haider 54 (1994) 41
Bow, J.S., L.M. Porter, M.J. Kim, R.W. Carpenter and R.F. Davis, Thin film Ti/6H-SiC interfacial reaction: high spatial resolution electron microscopy study 52 (1993) 289
Boyd, J.T., see Choo 57 (1995) 124
Bradley, S.A. and W.E. King, Foreword 51 (1993) vii
Brandow, S.L., see Turner 58 (1995) 425
Brandt, J., see Rübenkamm 58 (1995) 337
Braun, H.G., see Burmester 55 (1994) 55
Braun, N., see Rübenkamm 58 (1995) 337
Bricogne, C., see Voigt-Martin 56 (1994) 271
Brink, J., see Leapman 52 (1993) 157
Broeckx, J., M. Op de Beeck and D. Van Dyck, A useful approximation of the exit wave function in coherent STEM 60 (1995) 71
Brohan, P., see Rez 59 (1995) 159
Brown, L.M., see Ito 52 (1993) 347
Bruley, J., see Müllejans 53 (1994) 351
Bruley, J., see Brydson 59 (1995) 81
Bruley, J., see Rez 59 (1995) 159
Brydson, R., J. Bruley, H. Müllejans, C. Scheu and M. Rühle, Modelling the bonding at metal–ceramic interfaces using PEELS in the STEM 59 (1995) 81
Buckett, M.I. and K.L. Merkle, Determination of grain boundary volume expansion by HREM 56 (1994) 71
Bunn, R.D., see Joy 51 (1993) 1
Burgess, W.G., A.R. Preston, G.A. Botton, N.J. Zaluzec and C.J. Humphreys, Benefits of energy filtering for advanced convergent beam electron diffraction patterns 55 (1994) 276

Burgess, W.G., see Saunders 60 (1995) 311
Burmester, C., H.G. Braun and R.R. Schröder, A new quasi-confocal image plate scanner with improved spatial resolution and ideal detection efficiency 55 (1994) 55
Butler, B.D. and J.B. Cohen, What the latest diffraction techniques can tell us about an old material: steel 52 (1993) 238
Buttle, K., see Penczek 60 (1995) 393

Cai, Z.-X., see Zhu 52 (1993) 539
Campbell, G.H., see King 51 (1993) 128
Campbell, G.H., W.L. Wien, W.E. King, S.M. Foiles and M. Rühle, High-resolution electron microscopy investigation of the (710) twin in Nb 51 (1993) 247
Campbell, G.H., see King 56 (1994) 46
Cantow, H-J., see Wawkuschewski 58 (1995) 185
Carazo, J.M., see De la Fraga 60 (1995) 385
Carim, A.H. and T.E. Mitchell, 90° boundaries and associated interfacial and stand-off partial dislocations in $YBa_2Cu_3O_{7-x}$ 51 (1993) 228
Carpenter, R.W., see Bow 52 (1993) 289
Carragher, B.O., see Whittaker 58 (1995) 245
Carrascosa, J.L., see Vélez 60 (1995) 41
Carter, C.B., see Tietz 60 (1995) 241
Casanove, M.-J., see Hutchison 53 (1994) 91
Caspar, D., see Ruiz 55 (1994) 383
Castell, M.R., see Bleloch 54 (1994) 107
Castell, M.R., see Perovic 58 (1995) 104
Castiaux, A., A. Dereux, J.-P. Vigneron, C. Girard and O.J.F. Martin, Electromagnetic fields in two-dimensional models of near-field optical microscope tips 60 (1995) 1
Cates, C., see Ghaemi 57 (1995) 165
Cavalcoli, D., G. Matteucci and M. Muccini, Simulation of electron holographic contour maps of linear charged dislocations 57 (1995) 385
Cazaux, J., Correlations between ionization radiation damage and charging effects in transmission electron microscopy 60 (1995) 411
Čeh, M., see Gu 59 (1995) 215
Cerritelli, M.E., see Kocsis 60 (1995) 219
Cerva, H., V. Huber, W. Eckers and A. Mitwalsky, Specific preparation procedures for failure analysis of (sub)micron areas in silicon devices 52 (1993) 127
Cerva, H., see Thoma 53 (1994) 37
Chang, C., see Turner 58 (1995) 425
Chang, L., see Chen 54 (1994) 179
Chang, Y.C. and J.M. Howe, In situ HRTEM study of Ω precipitate dissolution in an Al–Cu–Mg–Ag alloy 51 (1993) 46
Chau, K.-L., see Kirkland 57 (1995) 355
Chen, C.Y. and W.M. Stobbs, The α-fringe contrast of thin twins in relation to the anomalous weak-beam contrast of stacking faults 58 (1995) 289
Chen, F.-R., see Chen 51 (1993) 316
Chen, F.R., S.K. Chiou, L. Chang and C.S. Hong, High-resolution electron microscopy of Cu/MgO and Pd/MgO interfaces 54 (1994) 179
Chen, J., see Hirayama 54 (1994) 9
Chen, J., see Ishizuka 60 (1995) 25
Chen, L.J., J.M. Liang, C.S. Liu, W.Y. Hsieh, J.H. Lin, T.L. Lee, M.H. Wang and W.J. Chen, High-resolution transmission electron microscopy investigation of interfaces in metal–silicon systems 54 (1994) 156
Chen, M., see Bolton 60 (1995) 247
Chen, W.-J. and F.-R. Chen, HRTEM study of atomic faceting of asymmetrical twin and asymmetrical hetero-twin boundaries in $NiSi_2/Si$ 51 (1993) 316
Chen, W.J., see Chen 54 (1994) 156
Chen, Y. and R.K. Kupka, Analysis of the near field image formation of dielectric gratings 57 (1995) 153
Cheng, N., see Kocsis 60 (1995) 219
Cheng, S.C., see Egerton 55 (1994) 43
Cheng, S.C., see Wang 59 (1995) 109
Cheng, T.Z., see Fu 54 (1994) 229
Cherns, D., see Hutchison 53 (1994) 91
Cherns, D. and J.P. Morniroli, Analysis of partial and stair-rod dislocations by large angle convergent beam electron diffraction 53 (1994) 167
Cherns, D., see Atici 58 (1995) 435
Chevalier, J.-P. and M.J. Hytch, Simulating the exit wave function for uniformly disordered systems 52 (1993) 253
Chevalier, J.-P., see Hytch 52 (1993) 415
Chevalier, J.P., see Hÿtch 58 (1995) 114
Chiang, A., see Sinclair 51 (1993) 41
Chiba, N., see Muramatsu 57 (1995) 141
Chiou, S.K., see Chen 54 (1994) 179
Chiu, W., see Leapman 52 (1993) 157
Choo, A.G., M.H. Chudgar, H.E. Jackson, G.N. De Brabander, M. Kumar and J.T. Boyd, Photon scanning tunneling microscopy of optical channel waveguides 57 (1995) 124
Chou, C.T., see Hutchison 53 (1994) 91
Chou, C.T., S.C. Anderson, D.J.H. Cockayne, A.Z. Sikorski and M.R. Vaughan, Surface relaxation of strained heterostructures revealed by Bragg line splitting in LACBED patterns 55 (1994) 334
Christensen, D.A., Analysis of near field tip patterns including object interaction using finite-difference time-domain calculations 57 (1995) 189
Chudgar, M.H., see Choo 57 (1995) 124
Clarke, D.R., see De Graef 52 (1993) 179
Claverie, A., see Liliental-Weber 52 (1993) 570
Cline, J.A. and M. Isaacson, Comparison of different modes of reflection in near-field optical imaging 57 (1995) 147
Cloninger, T.L., S. Balasubramaniam, B.D. Boudreau, J. Raja and R.J. Hocken, A simple technique for screening near-field probes 57 (1995) 223

Cockayne, D.J.H., see Chou 55 (1994) 334
Cohen, J.B., see Butler 52 (1993) 238
Cole, J.S.W., see Perovic 58 (1995) 104
Colliex, C., see Tencé 58 (1995) 42
Colliex, C., see Yuan 59 (1995) 149
Corbett, J.M., see Robertson 58 (1995) 175
Cowley, J.M., see Liu 52 (1993) 335
Cowley, J.M., see Tsai 52 (1993) 400
Cowley, J.M., see Liu 53 (1994) 333
Cowley, J.M., see Wang 55 (1994) 228
Cowley, J.M., see Hsu 55 (1994) 302
Cowley, J.M., Chromatic coherence and inelastic scattering in electron holography 57 (1995) 327
Cowley, J.M., see Huang 57 (1995) 391
Cowley, J.M., M.S. Hansen and S.-Y. Wang, Imaging modes with an annular detector in STEM 58 (1995) 18
Cowley, J.M., see Gajdardziska-Josifovska 58 (1995) 65
Cowley, J.M., see Mankos 58 (1995) 87
Crämer, K., see Wawkuschewski 58 (1995) 185
Craven, A.J., see Garvie 54 (1994) 83
Creuzet, F., see Piednoir 57 (1995) 282
Crone, M., see Prutton 59 (1995) 47
Crozier, P.A., see Pan 52 (1993) 487
Crozier, P.A., Quantitative elemental mapping of materials by energy-filtered imaging 58 (1995) 157
Csillag, S., see Yuan 59 (1995) 149
Cullen, S.L., C.B. Boothroyd and C.J. Humphreys, Interpretation of the {100} fringes in lattice images from the centre of carbon nanotubes 56 (1994) 127
Currie, J.E., see Robertson 58 (1995) 175
Cyrklaff, M. and W. Kühlbrandt, High-resolution electron microscopy of biological specimens in cubic ice 55 (1994) 141

Datye, A., see Völkl 58 (1995) 97
Datye, A.K., see Ramachandran 51 (1993) 282
Datye, A.K., see Yao 52 (1993) 282
Davis, R.F., see Bow 52 (1993) 289
Daw, M.S., see Mills 56 (1994) 79
Dawson, P., K.W. Smith, F. de Fornel and J.-P. Goudonnet, Imaging of surface plasmon launch and propagation using a photon scanning tunneling microscope 57 (1995) 287
Daykin, A.C., see Xiao 53 (1994) 325
Daykin, A.C., A report on speckle and coherent diffraction phenomena in selected-area transmission electron diffraction patterns 55 (1994) 121
Daykin, A.C., Letter to the Editor concerning Ultramicroscopy 53 (1994) 325–331 56 (1994) xv
Daykin, A.C. and A.K. Petford-Long, Quantitative mapping of the magnetic induction distribution using Foucault images formed in a transmission electron microscope 58 (1995) 365
De Brabander, G.N., see Choo 57 (1995) 124
De Fornel, F., see Dawson 57 (1995) 287
De Graef, M., D.R. Clarke and J.S. Speck, In situ domain multiplication and migration in the antiferroelectric ceramic PLSnZT 52 (1993) 179
De Hollander, R.B.G., N.F. van Hulst and R.P.H. Kooyman, Near field plasmon and force microscopy 57 (1995) 263
De Hosson, J.Th.M., see Verwerft 56 (1994) 135
De la Fraga, L.G., J. Dopazo and J.M. Carazo, Confidence limits for resolution estimation in image averaging by random subsampling 60 (1995) 385
De Meulenaere, P., D. Van Dyck, G. Van Tendeloo and J. Van Landuyt, Dynamical electron diffraction in substitutionally disordered column structures 60 (1995) 171
De Meulenaere, P., G. Van Tendeloo, J. Van Landuyt and D. Van Dyck, On the interpretation of HREM images of partially ordered alloys 60 (1995) 265
De Ruijter, W.J., see Smith 52 (1993) 591
De Ruijter, W.J., R. Sharma, M.R. McCartney and D.J. Smith, Measurement of lattice-fringe vectors from digital HREM images: experimental precision 57 (1995) 409
De Veirman, A.E.M., F.J.G. Hakkens and A.G. Dirks, Cross-sectional transmission electron microscopy studies of metallic multilayers 51 (1993) 306
Deem, M.W., see Treacy 52 (1993) 512
Deininger, C., G. Necker and J. Mayer, Determination of structure factors, lattice strains and accelerating voltage by energy-filtered convergent beam electron diffraction 54 (1994) 15
Delaney, A.H. and A. Belmont, Restoration of high-tilt electron micrographs using a focus series 56 (1994) 319
Den Dekker, A.J., see Van den Bos 60 (1995) 345
Dereux, A., see Castiaux 60 (1995) 1
DeRosier, D.J., see Ruiz 55 (1994) 383
Deutsch, T., see Bayle 56 (1994) 94
D'Hoore, A., see Vinckier 57 (1995) 337
Diaz-Avalos, R., see Ruiz 55 (1994) 383
Dietzsch, Ch., see Driesel 57 (1995) 45
Dijken, D.K., see Verwerft 56 (1994) 135
Dinges, C., H. Kohl and H. Rose, High-resolution imaging of crystalline objects by hollow-cone illumination 55 (1994) 91
Dinges, C., A. Berger and H. Rose, Simulation of TEM images considering phonon and electronic excitations 60 (1995) 49
Dirks, A.G., see De Veirman 51 (1993) 306
Disko, M.M., see Hunt 58 (1995) 55
Dong, F.X., see Goodman 55 (1994) 314
Doole, R.C., see Bithell 56 (1994) 172
Door, R. and D. Gängler, Multiple least-squares fitting for quantitative electron energy-loss spectroscopy – an experimental investigation using standard specimens 58 (1995) 197
Dopazo, J., see De la Fraga 60 (1995) 385

Dorset, D.L., S. Kopp, J.R. Fryer and W.F. Tivol, The Sayre equation in electron crystallography 57 (1995) 59
Doukhan, J.C., see Van Cappellen 53 (1994) 343
Downing, K.H., see Glaeser 52 (1993) 478
Downing, K.H., see Perkins 60 (1995) 283
Downing, K.H., see McEwen 60 (1995) 357
Dravid, V.P., see Wang 52 (1993) 523
Dravid, V.P., see Ravikumar 52 (1993) 557
Dravid, V.P., see Zhang 57 (1995) 103
Dravid, V.P., see Wang 59 (1995) 109
Driesel, W., Low-energy ion optical system with a liquid-metal ion source for imaging and processing solid structures 52 (1993) 65
Driesel, W., Ch. Dietzsch, H. Niedrig and B. Praprotnik, HV TEM in situ investigations of the tip shape of a gallium liquid-metal ion/electron emitter 57 (1995) 45
Duan, X.F., see Xin 53 (1994) 159
Ducastelle, F., see Barreteau 57 (1995) 11
Dudarev, S.L., see Peng 52 (1993) 312
Dudarev, S.L., L.-M. Peng and M.J. Whelan, Distorted wave approach to diffuse scattering in THEED and RHEED 52 (1993) 393
Dufner, D.C., HREM observations of the conversion of β-Sn into $PtSn_4$ in the Pt–Sn thin film system 52 (1993) 276
Duncan, M.D., see Seaver 57 (1995) 219
Dunin-Borkowski, R.E. and W.M. Stobbs, The defocus contrast of a θ' precipitate in Al–4wt%Cu: Fresnel fringe analysis applied to an atomically abrupt interface 52 (1993) 404
Dunkelberger, D.G., see Fan 55 (1994) 7
Dunn, R.C., E.V. Allen, S.A. Joyce, G.A. Anderson and X.S. Xie, Near-field fluorescent imaging of single proteins 57 (1995) 113
Dunn, R.C. and X.S. Xie, Characterization of the temporal behavior of ultrashort pulses emerging from a near-field fiber probe 57 (1995) 169
Duscher, G., see Gatts 59 (1995) 229

Eades, J.A., see Lordi 55 (1994) 284
Eades, J.A., see Liu 56 (1994) 253
Eades, J.A., see Ma 60 (1995) 137
Eaglesham, D., see Libera 52 (1993) 564
Eaglesham, D.J. and S.D. Berger, Energy filtering the "thermal diffuse" background in electron diffraction 53 (1994) 319
Eckers, W., see Cerva 52 (1993) 127
Egerton, R.F. and S.C. Cheng, Characterization of an analytical electron microscope with a NiO test specimen 55 (1994) 43
Egerton, R.F. and K. Wong, Some practical consequences of the Lorentzian angular distribution of inelastic scattering 59 (1995) 169
Ekenstedt, M.J., see Olsson 51 (1993) 215
Elich, K., see Voigt-Martin 57 (1995) 29
Ellisman, M.H., see Fan 52 (1993) 21
Ellisman, M.H., see Fan 52 (1993) 499
Ellisman, M.H., see Fan 55 (1994) 7
Ellisman, M.H., see Fan 55 (1994) 155
Endo, J., see Ru 53 (1994) 1
Endo, J., see Ru 55 (1994) 209
Endoh, H., see Kumao 54 (1994) 201
Endoh, H. and H. Hashimoto, Atomic resolution electron microscope images formed by Si L_3-ionization electrons 54 (1994) 351
Endoh, H., H. Hashimoto and Y. Makita, Theoretical and observed electron microscope images of impurity atoms in thin crystals formed by L-shell ionization electrons 56 (1994) 108
Engel, A., see Schabert 53 (1994) 147
Engelborghs, Y., see Vinckier 57 (1995) 337
Epstein, A., see Haider 54 (1994) 41
Ernst, F., see Hofmann 53 (1994) 205
Ewing, R.C., see Wang 51 (1993) 339
Exner, A., see Schattschneider 59 (1995) 241
Eyring, L., see Kang 52 (1993) 377
Eyring, L., see Tong 52 (1993) 388

Fan, G.Y. and M.H. Ellisman, High-sensitivity lens-coupled slow-scan CCD camera for transmission electron microscopy 52 (1993) 21
Fan, G.Y., P.J. Mercurio, S.J. Young and M.H. Ellisman, Telemicroscopy 52 (1993) 499
Fan, G.Y., D.G. Dunkelberger and M.H. Ellisman, Performance of thin foil scintillating screen for transmission electron microscopy 55 (1994) 7
Fan, G.Y. and M.H. Ellisman, Stereoscopy by tilted illumination in transmission electron microscopy 55 (1994) 155
Fan, H.F., see Fu 54 (1994) 229
Farrow, N.A. and F.P. Ottensmeyer, Automatic 3D alignment of projection images of randomly oriented objects 52 (1993) 141
Farrow, R.F.C., see Zhang 51 (1993) 298
Faruqi, A.R., see Henderson 60 (1995) 375
Firtel, M., W. Xu, G. Southam, P.J. Mulhern, B. Blackford, M.H. Jericho and T.J. Beveridge, Tip-induced displacement and imaging of a multilayered bacterial structure by scanning tunneling microscopy 55 (1994) 113
Flank, A.-M., see Hug 59 (1995) 121
Foiles, S.M., see Campbell 51 (1993) 247
Foiles, S.M., see Mills 56 (1994) 79
Frank, J., see Penczek 53 (1994) 251
Frank, J., see Ramani Lata 58 (1995) 381
Frank, J., see Liu 58 (1995) 393
Frank, J., see Penczek 60 (1995) 393
Friedman, S.L., see Krivanek 59 (1995) 267
Froehlich, F., see Kann 57 (1995) 251
Frost, A.E., see Seaver 57 (1995) 219
Frost, B., see Völkl 58 (1995) 97
Fryer, J.R., see Dorset 57 (1995) 59
Fu, Q., see Völkl 55 (1994) 75

Fu, Z.Q., D.X. Huang, F.H. Li, J.Q. Li, Z.X. Zhao, T.Z. Cheng and H.F. Fan, Incommensurate modulation in minute crystals revealed by combining high-resolution electron microscopy and electron diffraction 54 (1994) 229
Fujihira, M., H. Monobe, H. Muramatsu and T. Ataka, Measurements of lateral distribution of fluorescence intensities and fluorescence spectra of microareas by a combined SNOM and AFM 57 (1995) 118
Fujihira, M., see Muramatsu 57 (1995) 141
Fujihira, M., H. Monobe, H. Muramatsu and T. Ataka, Near-field optical microscopic recording on Langmuir–Blodgett (LB) films and chemically modified surfaces 57 (1995) 176
Fujimoto, F., A. Mazel and J. Sévely, Image formation by inelastically scattered electrons in TEM and STEM 55 (1994) 253
Fujita, H., see Mori 51 (1993) 31
Fujita, Y., see Kumao 54 (1994) 201
Fujiyoshi, Y., see Aoyama 57 (1995) 345
Fung, K.K., see Wang 60 (1995) 427
Furuya, K., see Ishikawa 56 (1994) 211

Gaber, B.P., see Turner 58 (1995) 425
Gajdardziska-Josifovska, M., see McCartney 53 (1994) 283
Gajdardziska-Josifovska, M. and M.R. McCartney, Elimination of thickness dependence from medium resolution electron holograms 53 (1994) 291
Gajdardziska-Josifovska, M., see Huang 57 (1995) 391
Gajdardziska-Josifovska, M., J.K. Weiss and J.M. Cowley, Studies of Mo/Si multilayers with coherent electron beams 58 (1995) 65
Gängler, D., see Door 58 (1995) 197
Garcia, N., see Vu Thien Binh 58 (1995) 307
Garvie, L.A.J. and A.J. Craven, Electron-beam-induced reduction of Mn^{4+} in manganese oxides as revealed by parallel EELS 54 (1994) 83
Garvie, L.A.J., see Rez 59 (1995) 159
Gatts, C., G. Duscher, H. Müllejans and M. Rühle, Analyzing line scan EELS data with neural pattern recognition 59 (1995) 229
Gebhardt, W., see Bauer 51 (1993) 221
Gemperle, A. and J. Gemperlová, Practical accuracy of grain misorientation measurements by Kikuchi line technique 60 (1995) 207
Gemperlová, J., see Gemperle 60 (1995) 207
Gesang, T., see Höper 60 (1995) 17
Ghaemi, H., C. Cates and B.B. Goldberg, Low temperature near field spectroscopy and microscopy 57 (1995) 165
Gibson, J.M., see Treacy 52 (1993) 31
Gibson, J.M., see Twesten 53 (1994) 223
Gibson, J.M., see Treacy 54 (1994) 93
Gibson, J.M., Breakdown of the weak-phase object approximation in amorphous objects and measurement of high-resolution electron optical parameters 56 (1994) 26
Gilles, B., see Bayle 56 (1994) 94
Gilmore, C.J., see Voigt-Martin 56 (1994) 271
Girard, C., see Castiaux 60 (1995) 1
Gjønnes, J. and J. Taftø, Bloch wave symmetry in electron diffraction 52 (1993) 445
Gladfelter, W.L., see Haugstad 54 (1994) 31
Glaeser, R.M. and K.H. Downing, High-resolution electron crystallography of protein molecules 52 (1993) 478
Glaeser, R.M., see Han 55 (1994) 1
Glaeser, R.M., see Perkins 60 (1995) 283
Glaeser, R.M., see McEwen 60 (1995) 357
Glas, F., The consequences of the atomic size effect in quantitative high resolution electron microscopy 60 (1995) 91
Gleyzes, P., A.C. Boccara and R. Bachelot, Near field optical microscopy using a metallic vibrating tip 57 (1995) 318
Goldberg, B.B., see Ghaemi 57 (1995) 165
Gong, H., Theory and computation for imaging in scanning transmission microscopy considering partial coherence in illumination 55 (1994) 373
Goodman, P. and P. Miller, Reassessment of the symmetry of the 221 PbBiSrCaCuO structure using LACBED and high-resolution SAD: the relevance of Cowley's theory of disorder scattering to a real-space structural analysis 52 (1993) 549
Goodman, P., Foreword to Festschrift for Gunter Lehmpfuhl 55 (1994) vii
Goodman, P., S. Matheson and F.X. Dong, Bloch-wave analysis of periodic surface contrast in zone-axis images 55 (1994) 314
Goringe, M.J., see Bithell 56 (1994) 172
Goudonnet, J.-P., see Dawson 57 (1995) 287
Govoni, D., see Merli 60 (1995) 229
Grassucci, R.A., see Penczek 53 (1994) 251
Greffet, J.-J., see Sentenac 57 (1995) 246
Grigorieff, N. and R. Henderson, Diffuse scattering in electron diffraction data from protein crystals 60 (1995) 295
Grogger, W., see Hofer 59 (1995) 15
Gross, L.J., see Lewis 56 (1994) 303
Gu, H., M. Čeh, S. Stemmer, H. Müllejans and M. Rühle, A quantitative approach for spatially-resolved electron energy-loss spectroscopy of grain boundaries and planar defects on a subnanometer scale 59 (1995) 215
Gubbens, A.J. and O.L. Krivanek, Applications of a post-column imaging filter in biology and materials science 51 (1993) 146
Gubbens, A.J., B. Kraus, O.L. Krivanek and P.E. Mooney, An imaging filter for high voltage electron microscopy 59 (1995) 255
Gubbens, A.J., see Krivanek 59 (1995) 267
Gubbens, A.J., see Meyer 59 (1995) 283
Gurevich, V.S. and M.N. Libenson, Surface polaritons propagation along micropipettes 57 (1995) 277

Hackney, S.A., T.M. Lillo, R.S. Kedia, Q.C. Horn and M.R. Plichta, Edge instabilities in thin plates studied by in situ transmission electron microscopy 51 (1993) 81
Haider, M., A. Epstein, P. Jarron and C. Boulin, A versatile, software configurable multichannel STEM detector for angle-resolved imaging 54 (1994) 41
Hakkens, F.J.G., see De Veirman 51 (1993) 306
Hallen, H.D., see LaRosa 57 (1995) 303
Hammel, M. and H. Rose, Optimum rotationally symmetric detector configurations for phase-contrast imaging in scanning transmission electron microscopy 58 (1995) 403
Han, B.-G., S.G. Wolf, J. Vonck and R.M. Glaeser, Specimen flatness of glucose-embedded biological materials for electron crystallography is affected significantly by the choice of carbon evaporation stock 55 (1994) 1
Han, P., see Zhang 57 (1995) 103
Hansen, M.S., see Cowley 58 (1995) 18
Harada, J., Effects of crystal surface roughness on X-ray CTR scattering 52 (1993) 233
Häring, R., see Schabert 53 (1994) 147
Harscher, A., G. Lang and H. Lichte, Interpretable resolution of 0.2 nm at 100 kV using electron holography 58 (1995) 79
Hashimoto, H., see Yokota 54 (1994) 207
Hashimoto, H., see Endoh 54 (1994) 351
Hashimoto, H., see Endoh 56 (1994) 108
Hashimoto, N., see Takahashi 56 (1994) 193
Hashimoto, T., see Joy 51 (1993) 1
Hashimoto, T., see Zhang 51 (1993) 21
Haskel, D., M. Sarikaya, M. Qian and E.A. Stern, EXELFS as a tool for quantifying phase distributions in materials 58 (1995) 353
Haugstad, G. and W.L. Gladfelter, Force–displacement measurements in a beam-reflection scanning force microscope: calibration issues 54 (1994) 31
Hawkes, P.W., Tables, handbooks, proceedings and a life 52 (1993) 205
Hawkes, P.W., Reading matter 56 (1994) 337
Hawkes, P.W., Volumes and issues 60 (1995) 325
Hayashi, T., see Homma 52 (1993) 187
Hecht, B., H. Heinzelmann and D.W. Pohl, Combined aperture SNOM/PSTM: best of both worlds? 57 (1995) 228
Heinzelmann, H., see Hecht 57 (1995) 228
Hellemans, L., see Vinckier 57 (1995) 337
Hembree, G.G., see Liu 52 (1993) 369
Henderson, R., see Grigorieff 60 (1995) 295
Henderson, R. and A.R. Faruqi, Analysis of sensitivity of cold stages on Philips CM12 to sources of vibration 60 (1995) 375
Hennemann, O.-D., see Höper 60 (1995) 17
Herbin, M., see Bonnet 60 (1995) 349
Hermann, C., see Safarov 57 (1995) 270
Herring, R.A., G. Pozzi, T. Tanji and A. Tonomura, Interferometry using convergent electron diffracted beams plus an electron biprism (CBED + EBI) 60 (1995) 153
Hertz, H.M., L. Malmqvist, L. Rosengren and K. Ljungberg, Optically trapped non-linear particles as probes for scanning near-field optical microscopy 57 (1995) 309
Heydenreich, J., see Rühle 56 (1994) ix
Heyvaert, I., see Vinckier 57 (1995) 337
Higgs, A.A., see Mankos 58 (1995) 87
Hillyard, S. and J. Silcox, Thickness effects in ADF STEM zone axis images 52 (1993) 325
Hillyard, S. and J. Silcox, Detector geometry, thermal diffuse scattering and strain effects in ADF STEM imaging 58 (1995) 6
Hirayama, T., J. Chen, T. Tanji and A. Tonomura, Dynamic observation of magnetic domains by on-line real-time electron holography 54 (1994) 9
Hocken, R.J., see Cloninger 57 (1995) 223
Hofer, F., P. Warbichler and W. Grogger, Imaging of nanometer-sized precipitates in solids by electron spectroscopic imaging 59 (1995) 15
Hoffmann, H., see Schuhrke 58 (1995) 319
Hofmann, D. and F. Ernst, Quantitative high-resolution transmission electron microscopy of the incoherent $\Sigma 3$ (211) boundary in Cu 53 (1994) 205
Hohenstein, M., see Bierwolf 56 (1994) 32
Høier, R., see Holmestad 52 (1993) 454
Høier, R., see Marthinsen 55 (1994) 268
Holmestad, R., O.L. Krivanek, R. Høier, K. Marthinsen and J.C.H. Spence, Commercial spectrometer modifications for energy filtering of electron diffraction patterns and images 52 (1993) 454
Holmestad, R., see Marthinsen 55 (1994) 268
Holton, M., see Valaskovic 57 (1995) 212
Homma, Y., M. Tomita and T. Hayashi, Atomic step imaging on silicon surfaces by scanning electron microscopy 52 (1993) 187
Honda, T., T. Tomita, T. Kaneyama and Y. Ishida, Field emission ultrahigh-resolution analytical electron microscope 54 (1994) 132
Honda, T., see Terauchi 54 (1994) 268
Hong, C.S., see Chen 54 (1994) 179
Höper, R., T. Gesang, W. Possart, O.-D. Hennemann and S. Boseck, Imaging elastic sample properties with an atomic force microscope operating in the tapping mode 60 (1995) 17
Horio, Y. and A. Ichimiya, Origin of phase shift phenomena in RHEED intensity oscillation curves 55 (1994) 321
Horita, Z., S. Matsumura and T. Baba, General formulation for ALCHEMI 58 (1995) 327
Horiuchi, S., see Takeda 56 (1994) 144
Horiuchi, T., see Sukedai 54 (1994) 192
Horn, Q.C., see Hackney 51 (1993) 81

Höschen, R., see Phillipp 56 (1994) 1
Hovmöller, S., see Zou 52 (1993) 436
Howe, J.M., see Chang 51 (1993) 46
Howie, A., see Perovic 52 (1993) 353
Howie, A., see Müllejans 52 (1993) 360
Howie, A., see Bleloch 54 (1994) 107
Howie, A., see Perovic 58 (1995) 104
Hsieh, W.Y., see Chen 54 (1994) 156
Hsu, T. and J.M. Cowley, Study of twinning with reflection electron microscopy (REM) 55 (1994) 302
Huang, D.X., see Fu 54 (1994) 229
Huang, Y., M. Gajdardziska-Josifovska and J.M. Cowley, REM in a UHV TEM for the observation of dynamic phase transformation processes on the $Cu_3Au(111)$ surface 57 (1995) 391
Huber, V., see Cerva 52 (1993) 127
Hug, G., G. Blanche, M. Jaouen, A.-M. Flank and J.J. Rehr, Simulation of the extended fine structure of K-shell edges in intermetallic ordered alloys 59 (1995) 121
Humphreys, C.J., see Boothroyd 52 (1993) 318
Humphreys, C.J., see Burgess 55 (1994) 276
Humphreys, C.J., see Cullen 56 (1994) 127
Humphreys, C.J., see Saunders 60 (1995) 311
Hunt, J.A., M.M. Disko, S.K. Behal and R.D. Leapman, Electron energy-loss chemical imaging of polymer phases 58 (1995) 55
Hutchison, J.L., C.T. Chou, M.-J. Casanove, D. Cherns, J.W. Steeds, D.A. Ashenford and B. Lunn, HREM of Ga_2Te_3: imaging of an ordered vacancy superlattice with enhanced contrast 53 (1994) 91
Hütten, A. and G. Thomas, Investigation of heterogeneous $Cu_{1-x}Co_x$ alloys with giant magnetoresistance 52 (1993) 581
Hytch, M.J., see Chevalier 52 (1993) 253
Hytch, M.J. and J.-P. Chevalier, Quantitative method of assessing the nature of local order from HREM images for SRO on crystalline sublattices 52 (1993) 415
Hÿtch, M.J. and W.M. Stobbs, The use of non-linear characteristics of a lattice fringe image for the characterisation of imaging parameters 53 (1994) 63
Hÿtch, M.J. and W.M. Stobbs, Quantitative comparison of high resolution TEM images with image simulations 53 (1994) 191
Hÿtch, M.J. and J.P. Chevalier, On the breakdown of Friedel's Law for coherent microdiffraction from amorphous materials 58 (1995) 114

Ichimiya, A., see Horio 55 (1994) 321
Ichinokawa, T., H. Itoh, A. Schmid, D. Winau and J. Kirschner, Scanning tunneling microscopic studies of surface reconstructed structures for metal/Si(100) systems 54 (1994) 116
Ikuhara, Y. and P. Pirouz, A high-resolution electron microscopy study of vanadium deposited on the basal plane of sapphire 52 (1993) 421
Ikuta, T., see Takai 54 (1994) 250
Ikuta, T., see Ando 54 (1994) 261
Inouye, Y., see Kawata 57 (1995) 313
Isaacson, M., Foreword to Near Field Optics 57 (1995) vii
Isaacson, M., see Cline 57 (1995) 147
Isaacson, M., see Klotzkin 58 (1995) 261
Ishida, Y., see Honda 54 (1994) 132
Ishikawa, N. and K. Furuya, Dual ion beam irradiation system interfaced with a transmission electron microscope and the observation of defect evolution in Ni during irradiation 56 (1994) 211
Ishikawa, T. and T. Wakabayashi, Proposal of alignment-independent classification of electron microscopic images with helical symmetry and its application to reconstituted thin filaments of skeletal muscle 57 (1995) 91
Ishizuka, K., Optimized sampling schemes for off-axis holography 52 (1993) 1
Ishizuka, K., Analysis of electron image detection efficiency of slow-scan CCD cameras 52 (1993) 7
Ishizuka, K., Resolution improvement by tilted single-sideband holography: preliminary experiments 53 (1994) 9
Ishizuka, K., Number of sampling points required for aberration correction using off-axis electron holography 53 (1994) 297
Ishizuka, K., T. Tanji, A. Tonomura, T. Ohno and Y. Murayama, Aberration correction using off-axis holography. I. Aberration assessment 53 (1994) 361
Ishizuka, K., T. Tanji, A. Tonomura, T. Ohno and Y. Murayama, Aberration correction using off-axis holography. II. Beyond the Scherzer limit 55 (1994) 197
Ishizuka, K., Coma-free alignment of a high-resolution electron microscope with threefold astigmatism 55 (1994) 407
Ishizuka, K. and J. Chen, HREM alignment aided by a real-time diffractometer using a liquid-crystal panel 60 (1995) 25
Isshiki, T., see Nishio 54 (1994) 301
Ito, Y., A.L. Bleloch, J.H. Paterson and L.M. Brown, Electron diffraction from gratings fabricated by electron beam nanolithography 52 (1993) 347
Itoh, H., see Ichinokawa 54 (1994) 116
Ivanov, Z.G., see Alarco 51 (1993) 239

Jackson, H.E., see Choo 57 (1995) 124
Jäger, W. and J. Mayer, Energy-filtered transmission electron microscopy of Si_mGe_n superlattices and Si–Ge heterostructures. I. Experimental results 59 (1995) 33
Jahncke, C.L., see LaRosa 57 (1995) 303
Jaouen, M., see Hug 59 (1995) 121
Jarron, P., see Haider 54 (1994) 41
Jayaram, G., see Xu 53 (1994) 15

Jefferson, D.A., see Tang 53 (1994) 137
Jericho, M.H., see Firtel 55 (1994) 113
Jiang, J.C. and K.H. Kuo, Quantitative evaluation of phasons in octogonal quasicrystals by high-resolution electron microscopy 54 (1994) 215
Johnson, A.W.S. and A.R. Preston, Some notes on the selection of structural chirality by CBED 55 (1994) 348
Josefsson, T.W., see Smith 55 (1994) 247
Josefsson, T.W., see Allen 55 (1994) 258
Josephs, R., see Lewis 56 (1994) 303
Jouffrey, B., see Schattschneider 53 (1994) 181
Joy, D.C., Y.-S. Zhang, X. Zhang, T. Hashimoto, R.D. Bunn, L. Allard and T.A. Nolan, Practical aspects of electron holography 51 (1993) 1
Joy, D.C., see Zhang 51 (1993) 21
Joyce, S.A., see Dunn 57 (1995) 113
Judkins, J., see Kann 57 (1995) 251

Kachi, T., see Tanaka 52 (1993) 533
Kambe, K. and C. Stampfl, Non-local pseudopotentials in the multi-slice method of calculating electron wavefunctions in crystals 55 (1994) 221
Kamimura, O., see Terauchi 54 (1994) 268
Kamiya, Y., K. Michishita and C. Tanaka, Intensity distribution of scintillation produced by high-energy electrons 54 (1994) 286
Kamiya, Y., see Kotera 54 (1994) 293
Kaneyama, T., see Honda 54 (1994) 132
Kaneyama, T., see Terauchi 54 (1994) 268
Kang, Z.C. and L. Eyring, Analysis of time-resolved, in-situ change in high-resolution electron microscopy 52 (1993) 377
Kann, J.L., T.D. Milster, F. Froehlich, R.W. Ziolkowski and J. Judkins, Numerical analysis of a two-dimensional near-field probe 57 (1995) 251
Karraï, K., see Kolb 57 (1995) 208
Karrasch, S., see Schabert 53 (1994) 147
Kato, K., see Khurshudov 60 (1995) 11
Kawasaki, M., see Kirkland 57 (1995) 355
Kawasaki, T. and J.M. Rodenburg, Deconvolving lens transfer functions in electron holograms 52 (1993) 248
Kawata, S. and Y. Inouye, Scanning probe optical microscopy using a metallic probe tip 57 (1995) 313
Kedia, R.S., see Hackney 51 (1993) 81
Kenny, P.G., I.R. Barkshire and M. Prutton, Three-dimensional scatter diagrams: application to surface analytical microscopy 56 (1994) 289
Kessler, P., see Lichte 52 (1993) 575
Khurshudov, A. and K. Kato, Wear of the atomic force microscope tip under light load, studied by atomic force microscopy 60 (1995) 11
Kim, H.S. and S.S. Sheinin, On effects of exit and entrance surface inclination on structure images 51 (1993) 109
Kim, M.J., see Bow 52 (1993) 289
Kim, Y., see Kisielowski 58 (1995) 131
Kimoto, T., see Watanabe 52 (1993) 465
Kimura, Y., see Ando 54 (1994) 261
Kimura, Y., see Ogai 54 (1994) 345
Kimura, Y., see Aoyama 57 (1995) 345
King, W.E., see Bradley 51 (1993) vii
King, W.E. and G.H. Campbell, Determination of thickness and defocus by quantitative comparison of experimental and simulated high-resolution images 51 (1993) 128
King, W.E., see Campbell 51 (1993) 247
King, W.E. and G.H. Campbell, Quantitative HREM using non-linear least-squares methods 56 (1994) 46
Kinoshita, C., Y. Tomokiyo and K. Nakai, In-situ observations of irradiation-induced phase transformations 56 (1994) 216
Kipp, S., R. Lacmann and M.A. Schneeweiss, Problems in temperature control performing in situ investigations with the scanning force microscope 57 (1995) 333
Kirkland, A.I., see Tang 53 (1994) 137
Kirkland, A.I., W.O. Saxton, K.-L. Chau, K. Tsuno and M. Kawasaki, Super-resolution by aperture synthesis: tilt series reconstruction in CTEM 57 (1995) 355
Kirschner, J., see Ichinokawa 54 (1994) 116
Kirtikar, A.S., see Sinclair 51 (1993) 41
Kisielowski, C., P. Schwander, F.H. Baumann, M. Seibt, Y. Kim and A. Ourmazd, An approach to quantitative high-resolution transmission electron microscopy of crystalline materials 58 (1995) 131
Kitagawa, T., see Tanaka 52 (1993) 533
Kizuka, T., see Tanaka 52 (1993) 533
Klotzkin, D. and M. Isaacson, Determination of Cr particle sizes in thin dilute Cr-in-Cu films from measurement statistics 58 (1995) 261
Knapp, H., see Schabert 53 (1994) 147
Ko, D.H. and R. Sinclair, In-situ dynamic high-resolution transmission electron microcopy: application to Pt/GaAs interfacial reactions 54 (1994) 166
Kocsis, E., M.E. Cerritelli, B.L. Trus, N. Cheng and A.C. Steven, Improved methods for determination of rotational symmetries in macromolecules 60 (1995) 219
Kohl, H., see Dinges 55 (1994) 91
Kohl, H., see Berger 55 (1994) 101
Kohl, H. and A. Berger, The resolution limit for elemental mapping in energy-filtering transmission electron microscopy 59 (1995) 191

Kolb, G., C. Obermüller, K. Karraï, G. Abstreiter, G. Böhm, G. Tränkle and G. Weimann, Photodetector with subwavelength spatial resolution 57 (1995) 208
Komatsu, M., see Mori 51 (1993) 31
Konkol, A., P.R. Wilshaw and G.R. Booker, Deconvolution method to obtain composition profiles from SEM backscattered electron signal profiles for bulk specimens 55 (1994) 183
Konkol, A., G.R. Booker and P.R. Wilshaw, Backscattered electron contrast on cross sections of interfaces and multilayers in the scanning electron microscope 58 (1995) 233
Konno, T.J., see Sinclair 56 (1994) 225
Kooyman, R.P.H., see De Hollander 57 (1995) 263
Kopelman, R., see Smith 57 (1995) 173
Kopelman, R., see Monson 57 (1995) 257
Kopp, S., see Dorset 57 (1995) 59
Kosobukin, V.A., see Safarov 57 (1995) 270
Kotera, M. and Y. Kamiya, Computer simulation of light emission by high-energy electrons in YAG single crystals 54 (1994) 293
Kovacs, J., see Tsai 57 (1995) 130
Kraus, B., see Gubbens 59 (1995) 255
Kraus, B., see Krivanek 59 (1995) 267
Krishnan, K.M., see Zhang 51 (1993) 298
Krivanek, O.L., see Gubbens 51 (1993) 146
Krivanek, O.L., see Holmestad 52 (1993) 454
Krivanek, O.L., Three-fold astigmatism in high-resolution transmission electron microscopy 55 (1994) 419
Krivanek, O.L. and P. Stadelmann, Foreword to EELSI 94 59 (1995) ix
Krivanek, O.L., see Gubbens 59 (1995) 255
Krivanek, O.L., S.L. Friedman, A.J. Gubbens and B. Kraus, An imaging filter for biological applications 59 (1995) 267
Krivanek, O.L., see Meyer 59 (1995) 283
Krivanek, O.L. and P.A. Stadelmann, Effect of three-fold astigmatism on high resolution electron micrographs 60 (1995) 103
Kruit, P., Editor's statement about co-authorship 56 (1994) xvi
Kruit, P., Editorial 60 (1995) v
Kruit, P., Hawkes and Kasper, Volume 3 60 (1995) 343
Krumbügel, M.A., see Totzeck 57 (1995) 160
Kudoh, J., see Shindo 54 (1994) 221
Kühlbrandt, W., see Cyrklaff 55 (1994) 141
Kuhn, W., see Bauer 51 (1993) 221
Kumao, A., Y. Fujita and H. Endoh, Growth of dendritic and needle tungsten oxide crystals studied by high-resolution electron microscopy 54 (1994) 201
Kumar, M., see Choo 57 (1995) 124
Kuo, K.H., see Jiang 54 (1994) 215
Kupka, R.K., see Chen 57 (1995) 153
Kurnikov, I., see Nevernov 58 (1995) 269
Kuwano, N., see Tomokiyo 54 (1994) 276
Lacmann, R., see Kipp 57 (1995) 333
Lai, G., see Ru 55 (1994) 209
Lakis, R.E., see Lyman 58 (1995) 25
Lampel, G., see Safarov 57 (1995) 270
Lançon, F., see Bayle 56 (1994) 94
Lang, G., see Harscher 58 (1995) 79
Langmore, J.P., see Monson 57 (1995) 257
LaRosa, A., C.L. Jahncke and H.D. Hallen, Time as a contrast mechanism in near-field imaging 57 (1995) 303
Lavoie, C., see Perovic 58 (1995) 104
Leapman, R.D., J. Brink and W. Chiu, Low-dose thickness measurement of glucose-embedded protein crystals by electron energy loss spectroscopy and STEM dark-field imaging 52 (1993) 157
Leapman, R.D., see Hunt 58 (1995) 55
Leapman, R.D. and S. Sun, Cryo-electron energy loss spectroscopy: observations on vitrified hydrated specimens and radiation damage 59 (1995) 71
Lee, T.L., see Chen 54 (1994) 156
Lehmann, M., E. Völkl and F. Lenz, Reconstruction of electron off-axis holograms: a new and fast alternative method 54 (1994) 335
Leifer, K., see Stadelmann 58 (1995) 35
Lentzen, M., see Thust 53 (1994) 101
Lenz, F., see Lichte 52 (1993) 575
Lenz, F., see Lehmann 54 (1994) 335
Lenz, F., see Völkl 55 (1994) 75
Lewis, M.R., L.J. Gross and R. Josephs, Variable pitch in frozen-hydrated sickle hemoglobin fibers: an image analysis model study 56 (1994) 303
Li, F.H., see Fu 54 (1994) 229
Li, J.Q., see Fu 54 (1994) 229
Liang, J.M., see Chen 54 (1994) 156
Libenson, M.N., see Gurevich 57 (1995) 277
Libera, M., D.A. Smith, L. Tsung and D. Eaglesham, High-spatial-resolution analysis of Ge layers in Si 52 (1993) 564
Lichte, H., Parameters for high-resolution electron holography 51 (1993) 15
Lichte, H., P. Kessler, F. Lenz and W.D. Rau, 0.1 nm information limit with the CM30FEG-Special Tübingen 52 (1993) 575
Lichte, H., see Schweda 53 (1994) 53
Lichte, H., see Schweda 54 (1994) 94
Lichte, H. and W.D. Rau, High-resolution electron holography with the CM30FEG-Special Tübingen 54 (1994) 310
Lichte, H., see Völkl 55 (1994) 75
Lichte, H., see Harscher 58 (1995) 79
Licoppe, C., see Piednoir 57 (1995) 282
Liliental-Weber, Z., F. Namavar and A. Claverie, Arsenic implantation into GaAs: a SOI technology for compound semiconductors? 52 (1993) 570

Lillo, T.M., see Hackney 51 (1993) 81
Lin, J.H., see Chen 54 (1994) 156
Lindsay, S.M., Editorial 60 (1995) vi
Link, P., see Bauer 51 (1993) 221
Liu, C.S., see Chen 54 (1994) 156
Liu, J. and J.M. Cowley, High-resolution scanning transmission electron microscopy 52 (1993) 335
Liu, J., G.G. Hembree, G.E. Spinnler and J.A. Venables, Nanometer-resolution surface analysis with Auger electrons 52 (1993) 369
Liu, M. and J.M. Cowley, Structures of carbon nanotubes studied by HRTEM and nanodiffraction 53 (1994) 333
Liu, Q., A simple and rapid method for determining orientations and misorientations of crystalline specimens in TEM 60 (1995) 81
Liu, W., see Sukedai 54 (1994) 192
Liu, Y., J.A. Eades and J. Mazumder, Solving the crystal structure of a submicrometer phase in TEM 56 (1994) 253
Liu, Y., P.A. Penczek, B.F. McEwen and J. Frank, A marker-free alignment method for electron tomography 58 (1995) 393
Ljungberg, K., see Hertz 57 (1995) 309
Lordi, S., Y. Ma and J.A. Eades, Comparison of calculated and experimental convergent-beam RHEED patterns from MgO(100) 55 (1994) 284
Lordi, S., see Ma 60 (1995) 137
Loubet, J.-L., see Mazeran 60 (1995) 33
Loubradou, M., J.M. Pénisson and R. Bonnet, Structural ledges at precipitate/matrix interfaces in a (Ni, Co) superalloy: atomic structures and elastic fields 51 (1993) 270
Lulli, G., A. Parisini and G. Mattei, Influence of electron-beam parameters on the radiation-induced formation of graphitic onions 60 (1995) 187
Lundberg, M. and M. Sundberg, New complex structures in the cesium–niobium–tungsten–oxide system revealed by HREM 52 (1993) 429
Lunn, B., see Hutchison 53 (1994) 91
Lyman, C.E., R.E. Lakis and H.G. Stenger, Jr., X-ray emission spectrometry of phase separation in Pt–Rh nanoparticles for nitric oxide reduction 58 (1995) 25

Ma, Y., see Lordi 55 (1994) 284
Ma, Y., S. Lordi and J.A. Eades, Symmetry analysis of the RHEED patterns from the Si(001)-2 × 1 surfaces 60 (1995) 137
Maeda, M., see Yasuda 56 (1994) 121
Magonov, S.N., see Wawkuschewski 58 (1995) 185
Maier, H.J., H. Renner and H. Mughrabi, Local lattice parameter measurements in cyclically deformed copper by convergent-beam electron diffraction 51 (1993) 136
Makita, Y., see Endoh 56 (1994) 108
Malmqvist, L., see Hertz 57 (1995) 309
Mankos, M., A.A. Higgs, M.R. Scheinfein and J.M. Cowley, Far-out-of-focus electron holography in a dedicated FEG STEM 58 (1995) 87
Marko, M., see Penczek 60 (1995) 393
Marks, L.D., see Xu 53 (1994) 15
Marks, L.D. and R. Plass, Partially coherent and holographic contrast transfer theory 55 (1994) 165
Marks, L.D., see Zhang 57 (1995) 103
Marlière, C., see Safarov 57 (1995) 270
Martelet, C., see Mazeran 60 (1995) 33
Marthinsen, K., see Holmestad 52 (1993) 454
Marthinsen, K., R. Holmestad and R. Høier, Analytical filtering of low-angle inelastic scattering contributions to CBED contrast 55 (1994) 268
Martin, O.J.F., see Castiaux 60 (1995) 1
Marty, A., see Bayle 56 (1994) 94
Massover, W.H., Positive staining of protein molecules for electron microscopy: polyiodination of the apoferritin shell in ferritin 52 (1993) 383
Matheson, S., see Goodman 55 (1994) 314
Matsumoto, T., T. Tanji and A. Tonomura, Phase-contrast visualization of an undecagold cluster by in-line electron holography 54 (1994) 317
Matsumura, S., see Tomokiyo 54 (1994) 276
Matsumura, S., see Horita 58 (1995) 327
Mattei, G. and A.M. Mazzone, Analysis of irradiated Ag and Si by molecular dynamics and simulated HREM images 58 (1995) 223
Mattei, G., see Lulli 60 (1995) 187
Mattei, G., see Merli 60 (1995) 229
Matteucci, G. and M. Muccini, On electron holographic mapping of electric and magnetic fields: recording and processing problems and field information reliability 53 (1994) 19
Matteucci, G., see Cavalcoli 57 (1995) 385
Mayer, J., see Deininger 54 (1994) 15
Mayer, J., see Berger 55 (1994) 101
Mayer, J., see Jäger 59 (1995) 33
Mazel, A., see Fujimoto 55 (1994) 253
Mazeran, P.-E., J.-L. Loubet, C. Martelet and A. Theretz, Under buffer SFM observation of immunospecies adsorbed on a cyano grafted silicon substrate 60 (1995) 33
Mazumder, J., see Liu 56 (1994) 253
Mazzone, A.M., see Mattei 58 (1995) 223
McCallum, B.C. and J.M. Rodenburg, Error analysis of crystalline ptychography in the STEM mode 52 (1993) 85
McCartney, M.R., see Smith 52 (1993) 591
McCartney, M.R. and M. Gajdardziska-Josifovska, Absolute measurement of normalized thickness, t/λ_i, from off-axis electron holography 53 (1994) 283
McCartney, M.R., see Gajdardziska-Josifovska 53 (1994) 291
McCartney, M.R., see De Ruijter 57 (1995) 409
McEwen, B.F., see Liu 58 (1995) 393

McEwen, B.F., K.H. Downing and R.M. Glaeser, The relevance of dose-fractionation in tomography of radiation-sensitive specimens 60 (1995) 357
McKernan, S., see Tietz 60 (1995) 241
McKittrick, T., see Vinckier 57 (1995) 337
Medvedev, V.K., Yu. Suchorski and J.H. Block, Lithium field desorption microscope: a new tool for surface investigations 53 (1994) 27
Meijer, G., see Van Tendeloo 51 (1993) 168
Melmed, A.J., see Spence 52 (1993) 473
Mercurio, P.J., see Fan 52 (1993) 499
Merkle, K.L., see Buckett 56 (1994) 71
Merli, P.G., A. Migliori, M. Nacucchi, D. Govoni and G. Mattei, On the resolution of semiconductor multilayers with a scanning electron microscope 60 (1995) 229
Merritt, G., see Monson 57 (1995) 257
Messerschmidt, U. and M. Bartsch, High-temperature straining stage for in situ experiments in the high-voltage electron microscope 56 (1994) 163
Meyer, C.E., C.B. Boothroyd, A.J. Gubbens and O.L. Krivanek, Measurement of TEM primary energy with an electron energy-loss spectrometer 59 (1995) 283
Michael, J.R., S.J. Plimpton and A.D. Romig, Jr., Parallel simulation of electron–solid interactions: a rapid aid for electron microscope data interpretation 51 (1993) 160
Michishita, K., see Kamiya 54 (1994) 286
Midgley, P.A., see Vincent 53 (1994) 271
Midgley, P.A., M. Saunders, R. Vincent and J.W. Steeds, Energy-filtered convergent-beam diffraction: examples and future prospects 59 (1995) 1
Migliori, A., see Merli 60 (1995) 229
Milat, O., see Amelinckx 51 (1993) 90
Miles, M.J., see Williamson 57 (1995) 235
Miller, M.L., see Wang 51 (1993) 339
Miller, P., see Goodman 52 (1993) 549
Milligan, R.A., see Whittaker 58 (1995) 245
Mills, M.J., M.S. Daw and S.M. Foiles, High-resolution transmission electron microscopy studies of dislocation cores in metals and intermetallic compounds 56 (1994) 79
Milster, T.D., see Kann 57 (1995) 251
Mitchell, T.E., see Carim 51 (1993) 228
Mitwalsky, A., see Cerva 52 (1993) 127
Möbus, G., see Phillipp 56 (1994) 1
Möbus, G. and M. Rühle, Structure determination of metal–ceramic interfaces by numerical contrast evaluation of HRTEM micrographs 56 (1994) 54
Moers, M.H.P., N.F. van Hulst, A.G.T. Ruiter and B. Bölger, Optical contrast in near-field techniques 57 (1995) 298
Möller, M., see Sheiko 53 (1994) 371
Monobe, H., see Fujihira 57 (1995) 118
Monobe, H., see Muramatsu 57 (1995) 141
Monobe, H., see Fujihira 57 (1995) 176
Monson, E., G. Merritt, S. Smith, J.P. Langmore and R. Kopelman, Implementation of an NSOM system for fluorescence microscopy 57 (1995) 257
Mooney, P.E., see Gubbens 59 (1995) 255
Morgiel, J., see Sinclair 51 (1993) 41
Mori, H., M. Komatsu and H. Fujita, Topics in in-situ experiments in the HVEM 51 (1993) 31
Mori, H., see Yasuda 56 (1994) 121
Morniroli, J.P., see Cherns 53 (1994) 167
Morniroli, J.P., see Redjaïmia 53 (1994) 305
Morrison, G.H., see Valaskovic 57 (1995) 212
Moskovits, M., see Tsai 57 (1995) 130
Moss, S.C., see Reinhard 52 (1993) 223
Muccini, M., see Matteucci 53 (1994) 19
Muccini, M., see Cavalcoli 57 (1995) 385
Mughrabi, H., see Maier 51 (1993) 136
Mulhern, P.J., see Firtel 55 (1994) 113
Müllejans, H., A.L. Bleloch, A. Howie and M. Tomita, Secondary electron coincidence detection and time of flight spectroscopy 52 (1993) 360
Müllejans, H. and J. Bruley, Improvements in detection sensitivity by spatial difference electron energy-loss spectroscopy at interfaces in ceramics 53 (1994) 351
Müllejans, H., see Brydson 59 (1995) 81
Müllejans, H., see Gu 59 (1995) 215
Müllejans, H., see Gatts 59 (1995) 229
Muller, D.A. and J. Silcox, Delocalization in inelastic scattering 59 (1995) 195
Muramatsu, H., see Fujihira 57 (1995) 118
Muramatsu, H., N. Chiba, T. Ataka, H. Monobe and M. Fujihira, Scanning near-field optic/atomic-force microscopy 57 (1995) 141
Muramatsu, H., see Fujihira 57 (1995) 176
Murase, T., see Sasaki 56 (1994) 184
Murayama, Y., see Ishizuka 53 (1994) 361
Murayama, Y., see Ishizuka 55 (1994) 197
Murphy, D.B., see Turner 58 (1995) 425
Muto, S., see Van Tendeloo 51 (1993) 168

Nacucchi, M., see Merli 60 (1995) 229
Nakai, K., see Kinoshita 56 (1994) 216
Namavar, F., see Liliental-Weber 52 (1993) 570
Necker, G., see Deininger 54 (1994) 15
Nellist, P.D. and J.M. Rodenburg, Beyond the conventional information limit: the relevant coherence function 54 (1994) 61
Nevernov, I., I. Kurnikov and C. Nicolini, Mechanical interactions in STM imaging of large insulating adsorbates 58 (1995) 269
Newsam, J.M., see Treacy 52 (1993) 512
Nicolini, C., see Nevernov 58 (1995) 269
Niedrig, H., see Driesel 57 (1995) 45

Nilsson, P.Å., see Alarco 51 (1993) 239
Nishio, K., T. Isshiki, H. Saijo and M. Shiojiri, Multi-slice calculation for InP crystals using different slices 54 (1994) 301
Nolan, T.A., see Joy 51 (1993) 1
Nolan, T.A., see Zhang 51 (1993) 21
Norris, T., see Smith 57 (1995) 173
Novotny, L., D.W. Pohl and P. Regli, Near-field, far-field and imaging properties of the 2D aperture SNOM 57 (1995) 180

Obermüller, C., see Kolb 57 (1995) 208
Ogai, K., Y. Kimura and R. Shimizu, Dynamic observation of a microelectric field in an oxide superconducting material by electron interference microscopy 54 (1994) 345
Ogawa, K., see Aoyama 57 (1995) 345
Ohkawa, T., see Yamaguchi 52 (1993) 306
Ohno, T., see Ishizuka 53 (1994) 361
Ohno, T., see Ishizuka 55 (1994) 197
Ohsuna, T., see Watanabe 52 (1993) 465
Oikawa, T., see Shindo 54 (1994) 221
Oki, K., see Tomokiyo 54 (1994) 276
Oku, T., see Shindo 54 (1994) 221
Okuyama, T., see Tomokiyo 54 (1994) 276
Olsson, E., M.J. Ekenstedt, S.-M. Wang, H. Qu and T.G. Andersson, Contradictory increase of critical layer thickness in $In_xGa_{1-x}Sb/GaAs$ heterostructures grown by MBE 51 (1993) 215
Olsson, E., see Alarco 51 (1993) 239
Op de Beeck, M., see Van Dyck 55 (1994) 435
Op de Beeck, M., see Broeckx 60 (1995) 71
Orr, B.G., see Smith 57 (1995) 173
Ortéga, J.M., see Piednoir 57 (1995) 282
Osakabe, N., see Ru 53 (1994) 1
Osaki, M., see Phillipp 56 (1994) 1
O'Shea, S.J., M.E. Welland and T.M.H. Wong, Influence of frictional forces on atomic force microscope images 52 (1993) 55
Ottensmeyer, F.P., see Farrow 52 (1993) 141
Ourmazd, A., see Kisielowski 58 (1995) 131

Paesler, M.A., see Yakobson 57 (1995) 204
Paesler, M.A., see Yakobson 57 (1995) 241
Pan, M. and P.A. Crozier, Quantitative imaging and diffraction of zeolites using a slow-scan CCD camera 52 (1993) 487
Parisini, A., see Lulli 60 (1995) 187
Paterson, J.H., see Ito 52 (1993) 347
Payne, D.A., see Zhang 57 (1995) 103
Payne, M., see Rez 59 (1995) 159
Penczek, P., M. Marko, K. Buttle and J. Frank, Double-tilt electron tomography 60 (1995) 393
Penczek, P.A., R.A. Grassucci and J. Frank, The ribosome at improved resolution: new techniques for merging and orientation refinement in 3D cryo-electron microscopy of biological particles 53 (1994) 251
Penczek, P.A., see Ramani Lata 58 (1995) 381
Penczek, P.A., see Liu 58 (1995) 393
Peng, L.-M. and S.L. Dudarev, Direct determination of crystal and surface structures in THEED 52 (1993) 312
Peng, L.-M., see Dudarev 52 (1993) 393
Peng, L.-M., see Wang 55 (1994) 67
Peng, L.-M. and J.M. Zuo, Direct retrieval of crystal structure factors in THEED 57 (1995) 1
Pénisson, J.M., Detection of substitutional atoms in a γ' phase by high-resolution electron microscopy 51 (1993) 264
Pénisson, J.M., see Loubradou 51 (1993) 270
Peretti, J., see Safarov 57 (1995) 270
Perkins, G.A., K.H. Downing and R.M. Glaeser, Crystallographic extraction and averaging of data from small image areas 60 (1995) 283
Perovic, D.D., C.J. Rossouw and A. Howie, Imaging elastic strains in high-angle annular dark field scanning transmission electron microscopy 52 (1993) 353
Perovic, D.D., M.R. Castell, A. Howie, C. Lavoie, T. Tiedje and J.S.W. Cole, Field-emission SEM imaging of compositional and doping layer semiconductor superlattices 58 (1995) 104
Petford-Long, A.K., see Daykin 58 (1995) 365
Phillipp, F., see Rühle 56 (1994) ix
Phillipp, F., R. Höschen, M. Osaki, G. Möbus and M. Rühle, New high-voltage atomic resolution microscope approaching 1 Å point resolution installed in Stuttgart 56 (1994) 1
Piednoir, A., F. Creuzet, C. Licoppe and J.M. Ortéga, Locally resolved infrared spectroscopy 57 (1995) 282
Pike, W.T., Energy-filtered microdiffraction in a dedicated scanning transmission electron microscope 51 (1993) 117
Pirouz, P. and J.W. Yang, Polytypic transformations in SiC: the role of TEM 51 (1993) 189
Pirouz, P., see Ikuhara 52 (1993) 421
Plass, R., see Marks 55 (1994) 165
Plichta, M.R., see Hackney 51 (1993) 81
Plimpton, S.J., see Michael 51 (1993) 160
Pohl, D.W., see Novotny 57 (1995) 180
Pohl, D.W., see Hecht 57 (1995) 228
Porter, L.M., see Bow 52 (1993) 289
Possart, W., see Höper 60 (1995) 17
Pozzi, G., see Herring 60 (1995) 153
Praprotnik, B., see Driesel 57 (1995) 45
Preston, A.R., see Burgess 55 (1994) 276
Preston, A.R., see Johnson 55 (1994) 348
Preston, A.R., see Saunders 60 (1995) 311
Prutton, M., see Kenny 56 (1994) 289

Prutton, M., I.R. Barkshire and M. Crone, Quantitative surface chemical mapping with Auger and backscattered electron signals 59 (1995) 47

Qian, M., see Haskel 58 (1995) 353
Qian, M., M. Sarikaya and E.A. Stern, Development of the EXELFS technique for high accuracy structural information 59 (1995) 137
Qian, W., see Spence 52 (1993) 473
Qian, W., see Spence 55 (1994) 19
Qu, H., see Olsson 51 (1993) 215
Quartuccio, M., see Tencé 58 (1995) 42

Radermacher, M., Three-dimensional reconstruction from random projections: orientational alignment via Radon transforms 53 (1994) 121
Raja, J., see Cloninger 57 (1995) 223
Ramachandran, A.S., S.L. Anderson and A.K. Datye, The effect of adsorbate and pretreatment on the shape and reactivity of silica-supported platinum particles 51 (1993) 282
Ramani Lata, K., P.A. Penczek and J. Frank, Automatic particle picking from electron micrographs 58 (1995) 381
Ranck, J.-L., see Ruiz 55 (1994) 383
Rau, W.D., see Lichte 52 (1993) 575
Rau, W.D., see Lichte 54 (1994) 310
Ravikumar, V. and V.P. Dravid, Atomic structure of undoped $\Sigma = 5$ symmetrical tilt grain boundary in strontium titanate 52 (1993) 557
Redjaïmia, A. and J.P. Morniroli, Application of microdiffraction to crystal structure identification 53 (1994) 305
Regli, P., see Novotny 57 (1995) 180
Rehr, J.J., see Hug 59 (1995) 121
Reinhard, L. and S.C. Moss, Recent studies of short-range order in alloys: the Cowley theory revisited 52 (1993) 223
Renner, H., see Maier 51 (1993) 136
Reuvekamp, E.M.C.M., see Sheiko 53 (1994) 371
Rez, P., Does phonon scattering give high-resolution images? 52 (1993) 260
Rez, P., J. Bruley, P. Brohan, M. Payne and L.A.J. Garvie, Review of methods for calculating near edge structure 59 (1995) 159
Richter, K., High-density morphologies of ice in high-pressure frozen biological specimens 53 (1994) 237
Robertson, M.D., J.E. Currie, J.M. Corbett and J.B. Webb, Determination of elastic strains in epitaxial layers by HREM 58 (1995) 175
Rodenburg, J.M., see McCallum 52 (1993) 85
Rodenburg, J.M., see Kawasaki 52 (1993) 248
Rodenburg, J.M., see Nellist 54 (1994) 61
Rogers, J.K., see Toledo-Crow 57 (1995) 293
Romig, Jr., A.D., see Michael 51 (1993) 160
Rose, H., see Dinges 55 (1994) 91
Rose, H., Correction of aberrations, a promising means for improving the spatial and energy resolution of energy-filtering electron microscopes 56 (1994) 11
Rose, H., see Hammel 58 (1995) 403
Rose, H., see Dinges 60 (1995) 49
Rosenauer, A., see Bauer 51 (1993) 221
Rosengren, L., see Hertz 57 (1995) 309
Rossouw, C.J., see Perovic 52 (1993) 353
Rossouw, C.J., see Allen 55 (1994) 258
Rossouw, C.J., Incoherent contrast under dynamical diffraction conditions 58 (1995) 211
Ru, Q., N. Osakabe, J. Endo and A. Tonomura, Electron holography available in a non-biprism transmission electron microscope 53 (1994) 1
Ru, Q., Digital analysis of Young's interference fringes 55 (1994) 15
Ru, Q., G. Lai, K. Aoyama, J. Endo and A. Tonomura, Principle and application of phase-shifting electron holography 55 (1994) 209
Rübenkamm, E., N. Braun, L. Bachmann, A. Bacher, J. Brandt, W. Baumeister and S. Weinkauf, Quantitative evaluation of heavy metal decoration on protein molecules: contrast, specificity and resolution 58 (1995) 337
Rubio, G., see Vélez 60 (1995) 41
Rühle, M., see Campbell 51 (1993) 247
Rühle, M., F. Phillipp, A. Seeger and J. Heydenreich, Foreword to High-Voltage and High-Resolution Electron Microscopy 56 (1994) ix
Rühle, M., see Phillipp 56 (1994) 1
Rühle, M., see Möbus 56 (1994) 54
Rühle, M., see Brydson 59 (1995) 81
Rühle, M., see Gu 59 (1995) 215
Rühle, M., see Gatts 59 (1995) 229
Ruiter, A.G.T., see Moers 57 (1995) 298
Ruiz, T., J.-L. Ranck, R. Diaz-Avalos, D. Caspar and D.J. DeRosier, Electron diffraction of helical particles 55 (1994) 383
Rukolaine, S.A., An approach to the numerical solution of the problem of electron scattering in thin crystals, based on the Galerkin method 54 (1994) 75

Safarov, V.I., V.A. Kosobukin, C. Hermann, G. Lampel, C. Marlière and J. Peretti, Near-field magneto-optics with polarization sensitive STOM 57 (1995) 270
Saijo, H., see Nishio 54 (1994) 301
Saka, H., see Sasaki 56 (1994) 184
Saldin, D.K. and J.C.H. Spence, On the mean inner potential in high- and low-energy electron diffraction 55 (1994) 397
Sarikaya, M., see Haskel 58 (1995) 353
Sarikaya, M., see Qian 59 (1995) 137
Sasaki, K., T. Murase and H. Saka, In-situ transmission electron microscopy of grain boundaries in $CuGa_2$ 56 (1994) 184

Sato, F., see Tanaka 55 (1994) 241
Sato, K., see Stobbs 58 (1995) 275
Saunders, M., see Midgley 59 (1995) 1
Saunders, M., D.M. Bird, N.J. Zaluzec, W.G. Burgess, A.R. Preston and C.J. Humphreys, Measurement of low-order structure factors for silicon from zone-axis CBED patterns 60 (1995) 311
Saxton, W.O., What is the focus variation method? Is it new? Is it direct? 55 (1994) 171
Saxton, W.O., see Kirkland 57 (1995) 355
Saxton, W.O., Simple prescriptions for estimating three-fold astigmatism 58 (1995) 239
Schabert, F., H. Knapp, S. Karrasch, R. Häring and A. Engel, Confocal scanning laser – scanning probe hybrid microscope for biological applications 53 (1994) 147
Schattschneider, P., B. Jouffrey, Ch. Tischler and H. Bangert, The chromatic image shift in spatially resolved EELS 53 (1994) 181
Schattschneider, P., see Schenner 55 (1994) 31
Schattschneider, P. and A. Exner, Progress in electron Compton scattering 59 (1995) 241
Scheinfein, M.R., see Mankos 58 (1995) 87
Schenner, M. and P. Schattschneider, Spatial resolution in selected-area EELS 55 (1994) 31
Scheu, C., see Brydson 59 (1995) 81
Schmid, A., see Ichinokawa 54 (1994) 116
Schneeweiss, M.A., see Kipp 57 (1995) 333
Schröder, R.R., see Burmester 55 (1994) 55
Schuhrke, T., J. Zweck and H. Hoffmann, The problem of absorption in the Fresnel fringe analysis 58 (1995) 319
Schwander, P., see Kisielowski 58 (1995) 131
Schweda, E., J. Strähle, H. Lichte and E. Völkl, Combination of high-resolution electron imaging and holography in the investigation of the modulated structure of $Zr_4ON_3F_5$ 53 (1994) 53
Schweda, E., J. Strähle, H. Lichte and E. Völkl, Erratum to "Combination of high-resolution electron imaging and holography in the investigation of the modulated structure of $Zr_4ON_3F_5$" [Ultramicroscopy 53 (1994) 53–62] 54 (1994) 94
Seaver, M., M.D. Duncan and A.E. Frost, Near-field optical microscopy at the liquid/air interface 57 (1995) 219
Seeger, A., see Rühle 56 (1994) ix
Seibt, M., see Kisielowski 58 (1995) 131
Seiferth, F., see Toledo-Crow 57 (1995) 293
Semet, V., see Vu Thien Binh 58 (1995) 307
Sentenac, A. and J.-J. Greffet, Study of the features of PSTM images by means of a perturbative approach 57 (1995) 246
Sévely, J., see Fujimoto 55 (1994) 253
Shankland, K., see Voigt-Martin 56 (1994) 271
Shapiro, A.J., see Wang 60 (1995) 115
Sharma, R., see De Ruijter 57 (1995) 409
Sheiko, S.S., M. Möller, E.M.C.M. Reuvekamp and H.W. Zandbergen, Evaluation of the probing profile of scanning force microscopy tips 53 (1994) 371
Sheinin, S.S., see Kim 51 (1993) 109
Shimizu, R., see Takai 54 (1994) 250
Shimizu, R., see Ando 54 (1994) 261
Shimizu, R., see Ogai 54 (1994) 345
Shindo, D., T. Oku, J. Kudoh and T. Oikawa, Quantitative high-resolution electron microscopy of a high-T_c superconductor $Tl_2Ba_2Cu_1O_y$ with the imaging plate 54 (1994) 221
Shiojiri, M., see Nishio 54 (1994) 301
Sikorski, A.Z., see Chou 55 (1994) 334
Silcox, J., see Hillyard 52 (1993) 325
Silcox, J., see Hillyard 58 (1995) 6
Silcox, J., see Muller 59 (1995) 195
Sinclair, R., J. Morgiel, A.S. Kirtikar, I.-W. Wu and A. Chiang, Direct observation of crystallization in silicon by in situ high-resolution electron microscopy 51 (1993) 41
Sinclair, R., see Ko 54 (1994) 166
Sinclair, R. and T.J. Konno, In situ HREM: application to metal-mediated crystallization 56 (1994) 225
Small, M., see Smith 51 (1993) 328
Smith, A.E. and T.W. Josefsson, The effect of a non-Hermitian crystal potential on the scattering matrix in reflection electron diffraction 55 (1994) 247
Smith, D.A., M. Small and C. Stanis, Electron microscopy of the grain structure of metal films and lines 51 (1993) 328
Smith, D.A., see Libera 52 (1993) 564
Smith, D.J. and J.C.H. Spence, Foreword to Aspects of Electron Microscopy, Diffraction, Crystallography and Spectroscopy 52 (1993) vii
Smith, D.J., see Yao 52 (1993) 282
Smith, D.J., W.J. de Ruijter, M.R. McCartney and J.K. Weiss, Progress towards quantitative high-resolution electron microscopy 52 (1993) 591
Smith, D.J., see De Ruijter 57 (1995) 409
Smith, D.J., Foreword to Microscopy with Field Emission Electron Sources 58 (1995) vii
Smith, K.W., see Dawson 57 (1995) 287
Smith, S., B.G. Orr, R. Kopelman and T. Norris, 100 femtosecond/100 nanometer near-field probe 57 (1995) 173
Smith, S., see Monson 57 (1995) 257
Sopéna, P., see Tournier-Lasserve 58 (1995) 123
Southam, G., see Firtel 55 (1994) 113
Spargo, A.E.C., see Beeching 52 (1993) 243
Spargo, A.E.C., M.J. Beeching and L.J. Allen, Inversion of electron scattering intensity for crystal structure analysis 55 (1994) 329
Speck, J.S., see De Graef 52 (1993) 179

Spence, J., W. Qian and X. Zhang, Contrast and radiation damage in point-projection electron imaging of purple membrane at 100 V 55 (1994) 19
Spence, J.C.H., see Smith 52 (1993) vii
Spence, J.C.H., see Holmestad 52 (1993) 454
Spence, J.C.H., W. Qian and A.J. Melmed, Experimental low-voltage point-projection microscopy and its possibilities 52 (1993) 473
Spence, J.C.H., Reflection electron microscopy of buried interfaces in the transmission geometry 55 (1994) 293
Spence, J.C.H., see Saldin 55 (1994) 397
Spinnler, G.E., see Liu 52 (1993) 369
Stadelmann, P., K. Leifer and C. Verdon, EDS and EELS using a TEM-FEG microscope 58 (1995) 35
Stadelmann, P., see Krivanek 59 (1995) ix
Stadelmann, P.A., see Krivanek 60 (1995) 103
Stampfl, C., see Kambe 55 (1994) 221
Stanis, C., see Smith 51 (1993) 328
Steeds, J.W., see Hutchison 53 (1994) 91
Steeds, J.W., see Midgley 59 (1995) 1
Stemmer, S., see Gu 59 (1995) 215
Stenger, Jr., H.G., see Lyman 58 (1995) 25
Stepantsov, E.A., see Alarco 51 (1993) 239
Stern, E.A., see Haskel 58 (1995) 353
Stern, E.A., see Qian 59 (1995) 137
Steven, A.C., see Kocsis 60 (1995) 219
Stobbs, S.H., see Stobbs 52 (1993) 267
Stobbs, S.H., K. Sato and W.M. Stobbs, The HREM use of the FEGTEM for the study of interfaces 58 (1995) 275
Stobbs, W.M. and S.H. Stobbs, Spatial coherence effects in the use of high resolution approaches for the characterisation of the compositional abruptness of an interface 52 (1993) 267
Stobbs, W.M., see Dunin-Borkowski 52 (1993) 404
Stobbs, W.M., see Hÿtch 53 (1994) 63
Stobbs, W.M., see Hÿtch 53 (1994) 191
Stobbs, W.M., see Stobbs 58 (1995) 275
Stobbs, W.M., see Chen 58 (1995) 289
Stobbs, W.M., see Botton 59 (1995) 93
Strähle, J., see Schweda 53 (1994) 53
Strähle, J., see Schweda 54 (1994) 94
Su, D.S., M. Swoboda and E. Zeitler, Single-electron excitation of amorphous carbon observed with energy filter 53 (1994) 97
Su, D.S. and H.F. Wang, Atomic ratios determined by EELS under parallel and convergent illumination conditions 57 (1995) 323
Su, D.S., H.F. Wang and E. Zeitler, The influence of plural scattering on EELS elemental analysis 59 (1995) 181
Suchorski, Yu., see Medvedev 53 (1994) 27
Sukedai, E., W. Liu, M. Awaji and T. Horiuchi, Investigation of atomic structure of ω-phase crystals in Ti–Mo alloys using high-resolution electron microscopy 54 (1994) 192
Sukharev, Y., see Zou 52 (1993) 436
Sun, S., see Leapman 59 (1995) 71
Sundberg, M., see Lundberg 52 (1993) 429
Swoboda, M., see Su 53 (1994) 97

Tafreshi, M.A., see Yuan 59 (1995) 149
Taftø, J., see Gjønnes 52 (1993) 445
Takahashi, H., N. Hashimoto and S. Watanabe, Defect-flow-induced grain boundary migration with segregation under electron irradiation 56 (1994) 193
Takai, Y., Y. Taniguchi, T. Ikuta and R. Shimizu, Spherical-aberration-free observation of profile images of the Au(011) surface by defocus-modulation image processing 54 (1994) 250
Takai, Y., see Ando 54 (1994) 261
Takeda, S. and S. Horiuchi, Electron-diffraction channeling effect on defect formation in Si with ⟨110⟩ zone-axis incidence 56 (1994) 144
Tanaka, C., see Kamiya 54 (1994) 286
Tanaka, M., see Terauchi 54 (1994) 268
Tanaka, M., M. Terauchi and F. Sato, Observation of fourfold rotoinversion symmetry by convergent-beam electron diffraction 55 (1994) 241
Tanaka, N., T. Kitagawa, T. Kachi and T. Kizuka, Direct observation of epitaxially grown C_{60} crystals and molecules on vacuum-deposited MgO films 52 (1993) 533
Tang, D., A.I. Kirkland and D.A. Jefferson, Optimisation of high-resolution image simulations. II. Image selection in reciprocal space 53 (1994) 137
Taniguchi, Y., see Takai 54 (1994) 250
Taniguchi, Y., see Ando 54 (1994) 261
Tanji, T., see Ishizuka 53 (1994) 361
Tanji, T., see Hirayama 54 (1994) 9
Tanji, T., see Matsumoto 54 (1994) 317
Tanji, T., see Ishizuka 55 (1994) 197
Tanji, T., see Herring 60 (1995) 153
Taylor, K.A., see Winkler 55 (1994) 357
Tencé, M., M. Quartuccio and C. Colliex, PEELS compositional profiling and mapping at nanometer spatial resolution 58 (1995) 42
Terauchi, M., K. Tsuda, O. Kamimura, M. Tanaka, T. Kaneyama and T. Honda, Observation of lattice fringes in convergent-beam electron diffraction patterns 54 (1994) 268
Terauchi, M., see Tanaka 55 (1994) 241
Theretz, A., see Mazeran 60 (1995) 33
Thibault, J., see Bayle 56 (1994) 94
Thoma, S. and H. Cerva, Comparison of the information content in ⟨110⟩- and ⟨100⟩-projected high-resolution transmission electron microscope images for the quantitative analysis of AlAs/GaAs interfaces 53 (1994) 37
Thomas, G., see Hütten 52 (1993) 581
Thomas, G., Microstructural analyses of advanced inorganic materials 54 (1994) 145

Thust, A., M. Lentzen and K. Urban, Non-linear reconstruction of the exit plane wave function from periodic high-resolution electron microscopy images 53 (1994) 101
Tiedje, T., see Perovic 58 (1995) 104
Tietz, L.A., C.B. Carter and S. McKernan, Top–bottom effects in double diffraction 60 (1995) 241
Tischler, Ch., see Schattschneider 53 (1994) 181
Tivol, W.F., see Dorset 57 (1995) 59
Toledo-Crow, R., J.K. Rogers, F. Seiferth and M. Vaez-Iravani, Contrast mechanisms and imaging modes in near field optical microscopy 57 (1995) 293
Tomita, M., see Homma 52 (1993) 187
Tomita, M., see Müllejans 52 (1993) 360
Tomita, M. and A.L. Bleloch, Low energy (< 50 eV) secondary electron separator for nm-scale SE spectroscopy and imaging in STEM 54 (1994) 125
Tomita, T., see Honda 54 (1994) 132
Tomokiyo, Y., S. Matsumura, T. Okuyama, T. Yasunaga, N. Kuwano and K. Oki, Dynamical diffraction effect on HOLZ-pattern geometry in Si–Ge alloys and determination of local lattice parameter 54 (1994) 276
Tomokiyo, Y., see Kinoshita 56 (1994) 216
Tong, J., J.C. Wheatley and L. Eyring, The effect of an electric field on the crystallization of gel-derived alumina precursors observed in situ in the TEM 52 (1993) 388
Tonomura, A., see Ru 53 (1994) 1
Tonomura, A., see Ishizuka 53 (1994) 361
Tonomura, A., see Hirayama 54 (1994) 9
Tonomura, A., see Matsumoto 54 (1994) 317
Tonomura, A., see Ishizuka 55 (1994) 197
Tonomura, A., see Ru 55 (1994) 209
Tonomura, A., see Herring 60 (1995) 153
Totzeck, M. and M.A. Krumbügel, Test of various diffraction theories in the near field of phase objects 57 (1995) 160
Tournier-Lasserve, V., A. Boudet and P. Sopéna, Artefacts and their healing in ultramicrotomy of side-chain liquid-crystal polymers 58 (1995) 123
Tränkle, G., see Kolb 57 (1995) 208
Treacy, M.M.J. and J.M. Gibson, Coherence and multiple scattering in "Z-contrast" images 52 (1993) 31
Treacy, M.M.J., J.M. Newsam and M.W. Deem, Simulation of electron diffraction patterns from partially ordered layer lattices 52 (1993) 512
Treacy, M.M.J. and J.M. Gibson, Erratum to "Coherence and multiple scattering in 'Z-contrast' images" [Ultramicroscopy 52 (1993) 31–53] 54 (1994) 93
Trus, B.L., see Kocsis 60 (1995) 219
Tsai, D.P., J. Kovacs and M. Moskovits, Applications of apertured photon scanning tunnelling microscopy (APSTM) 57 (1995) 130
Tsai, F. and J.M. Cowley, Observation of planar defects by reflection electron microscopy 52 (1993) 400
Tsuda, K., see Terauchi 54 (1994) 268
Tsung, L., see Libera 52 (1993) 564
Tsuno, K., Simulation of a Wien filter as beam separator in a low energy electron microscope 55 (1994) 127
Tsuno, K., see Kirkland 57 (1995) 355
Turner, D.C., C. Chang, S.L. Brandow, D.B. Murphy and B.P. Gaber, Use of a repositionable substrate to acquire and compare distinct atomic force microscope images of a field of microtubules 58 (1995) 425
Twesten, R.D. and J.M. Gibson, Kinematic analysis of transmission electron diffraction data from Si(111)-7 × 7 53 (1994) 223
Tzalenchuk, A.Ya., see Alarco 51 (1993) 239

Uchida, Y., N. Wang and E. Zeitler, The alloying effect of Ag on the reconstruction in Au(111) and (100) surfaces observed by REM 55 (1994) 308
Unwin, N., see Berriman 56 (1994) 241
Urban, K., see Thust 53 (1994) 101

Vaez-Iravani, M., see Toledo-Crow 57 (1995) 293
Valaskovic, G.A., M. Holton and G.H. Morrison, Biological near-field scanning optical microscopy: instrumentation and sample issues for shear-force feedback 57 (1995) 212
Van Cappellen, E. and J.C. Doukhan, Quantitative transmission X-ray microanalysis of ionic compounds 53 (1994) 343
Van den Bos, A. and A.J. den Dekker, Ultimate resolution in the presence of coherence 60 (1995) 345
Van der Steen, A.C., see Verwerft 56 (1994) 135
Van Dyck, D. and M. Op de Beeck, Announcement: Comparison and test of HRTEM image simulation programs 55 (1994) 435
Van Dyck, D., see Broeckx 60 (1995) 71
Van Dyck, D., see De Meulenaere 60 (1995) 171
Van Dyck, D., see De Meulenaere 60 (1995) 265
Van Haesendonck, C., see Vinckier 57 (1995) 337
Van Hulst, N.F., see De Hollander 57 (1995) 263
Van Hulst, N.F., see Moers 57 (1995) 298
Van Labeke, D., see Barchiesi 57 (1995) 196
Van Landuyt, J., see Zhang 54 (1994) 237
Van Landuyt, J., see Zhang 55 (1994) 25
Van Landuyt, J., see De Meulenaere 60 (1995) 171
Van Landuyt, J., see De Meulenaere 60 (1995) 265
Van Loosdrecht, P.H.M., see Van Tendeloo 51 (1993) 168
Van Tendeloo, G., see Amelinckx 51 (1993) 90
Van Tendeloo, G., S. Amelinckx, S. Muto, M.A. Verheijen, P.H.M. van Loosdrecht and G. Meijer, Structures and phase transitions in C_{60} and C_{70} fullerites 51 (1993) 168

Van Tendeloo, G., see Zhang 54 (1994) 237
Van Tendeloo, G., see Zhang 55 (1994) 25
Van Tendeloo, G., see De Meulenaere 60 (1995) 171
Van Tendeloo, G., see De Meulenaere 60 (1995) 265
Vaughan, M.R., see Chou 55 (1994) 334
Vautrot, P., see Bonnet 60 (1995) 349
Vélez, M., G. Rubio, N. Agraït, J.L. Carrascosa and S. Vieira, Reversed metal replicas of freeze-dried proteins to be visualized with the scanning tunneling microscope 60 (1995) 41
Venables, J.A., see Liu 52 (1993) 369
Verdon, C., see Stadelmann 58 (1995) 35
Verheijen, M.A., see Van Tendeloo 51 (1993) 168
Verwerft, M., D.K. Dijken, J.Th.M. de Hosson and A.C. van der Steen, On the role of dislocations in heavily strained $YBa_2Cu_3O_{7-\delta}$ 56 (1994) 135
Vieira, S., see Vélez 60 (1995) 41
Vigneron, J.-P., see Castiaux 60 (1995) 1
Vincent, R. and P.A. Midgley, Double conical beam-rocking system for measurement of integrated electron diffraction intensities 53 (1994) 271
Vincent, R., see Midgley 59 (1995) 1
Vinckier, A., I. Heyvaert, A. D'Hoore, T. McKittrick, C. Van Haesendonck, Y. Engelborghs and L. Hellemans, Immobilizing and imaging microtubules by atomic force microscopy 57 (1995) 337
Voigt-Martin, I.G., D.H. Yan, C.J. Gilmore, K. Shankland and C. Bricogne, The use of maximum entropy and likelihood ranking to determine the crystal structure of 4-(4′-(N,N-dimethyl)aminobenzylidene)-pyrazolidine-3,5-dione at 1.4 Å resolution from electron diffraction and HREM image data 56 (1994) 271
Voigt-Martin, I.G., D.H. Yan, R. Wortmann and K. Elich, The use of simulation methods to obtain the structure and conformation of 10-cyano-9,9′-bianthryl by electron diffraction and high-resolution imaging 57 (1995) 29
Völkl, E., see Schweda 53 (1994) 53
Völkl, E., see Schweda 54 (1994) 94
Völkl, E., see Lehmann 54 (1994) 335
Völkl, E., F. Lenz, Q. Fu and H. Lichte, Density correction of photographic material for further image processing in electron microscopy 55 (1994) 75
Völkl, E., L.F. Allard, A. Datye and B. Frost, Advanced electron holography: a new algorithm for image processing and a standardized quality test for the FEG electron microscope 58 (1995) 97
Von Harrach, H.S., Instrumental factors in high-resolution FEG STEM 58 (1995) 1
Vonck, J., see Han 55 (1994) 1
Vu Thien Binh, V. Semet and N. Garcia, Nanometric observations at low energy by Fresnel projection microscopy: carbon and polymer fibres 58 (1995) 307
Wakabayashi, T., see Ishikawa 57 (1995) 91
Walsh, C.A., see Bleloch 54 (1994) 107
Wang, H.F., see Su 57 (1995) 323
Wang, H.F., see Su 59 (1995) 181
Wang, L. and J.M. Cowley, Electron channelling effects at high incident angles in convergent beam reflection high energy electron diffraction 55 (1994) 228
Wang, L.M., M.L. Miller and R.C. Ewing, HRTEM study of displacement cascade damage in krypton-ion-irradiated silicate – olivine 51 (1993) 339
Wang, M.H., see Chen 54 (1994) 156
Wang, N., see Uchida 55 (1994) 308
Wang, N. and K.K. Fung, Preparation of TEM plan-view and cross-sectional specimens of ZnSe/GaAs epilayers by chemical thinning and argon ion milling 60 (1995) 427
Wang, S.-M., see Olsson 51 (1993) 215
Wang, S.-Y., see Cowley 58 (1995) 18
Wang, S.Q. and L.-M. Peng, LACBED determination of structure factors and alloy composition of GeSi/Si SLS 55 (1994) 67
Wang, Y.Y., H. Zhang and V.P. Dravid, Electronic structure and dielectric function of oxide superconductors via transmission EELS with a cold field emission TEM 52 (1993) 523
Wang, Y.Y., see Zhang 57 (1995) 103
Wang, Y.Y., S.C. Cheng, V.P. Dravid and F.C. Zhang, Momentum-transfer resolved electron energy loss spectroscopy of solids: problems, solutions and applications 59 (1995) 109
Wang, Z.L. and J. Bentley, In-situ dynamic processes on cleaved α-alumina bulk crystal surfaces imaged by reflection electron microscopy 51 (1993) 64
Wang, Z.L., Thermal diffuse scattering in high-resolution electron holography 52 (1993) 504
Wang, Z.L., Dislocation contrast in high-angle hollow-cone dark-field TEM 53 (1994) 73
Wang, Z.L. and A.J. Shapiro, Energy-filtering and composition-sensitive imaging in surface and interface studies using HREM 60 (1995) 115
Warbichler, P., see Hofer 59 (1995) 15
Watanabe, D., T. Ohsuna and T. Kimoto, Modulated structures in the Cu–Au and (CuAu)–Ag alloys with antiphase structures of CuAu(II) type 52 (1993) 465
Watanabe, S., see Takahashi 56 (1994) 193
Wawkuschewski, A., K. Crämer, H-J. Cantow and S.N. Magonov, Optimization of experiment in scanning force microscopy of polymers 58 (1995) 185
Webb, J.B., see Robertson 58 (1995) 175
Weickenmeier, A.L., see Zuo 57 (1995) 375
Weimann, G., see Kolb 57 (1995) 208
Weinkauf, S., see Rübenkamm 58 (1995) 337
Weiss, J.K., see Smith 52 (1993) 591
Weiss, J.K., see Gajdardziska-Josifovska 58 (1995) 65

Welland, M.E., see O'Shea 52 (1993) 55
Werner, H., see Zhang 55 (1994) 25
Wheatley, J.C., see Tong 52 (1993) 388
Whelan, M.J., see Dudarev 52 (1993) 393
Whelan, M.J., Preface to Festschrift for Professor Hashimoto 54 (1994) 99
Whittaker, M., B.O. Carragher and R.A. Milligan, PHOELIX: a package for semi-automated helical reconstruction 58 (1995) 245
Wien, W.L., see Campbell 51 (1993) 247
Wilbrandt, P.-J., A simple concept for better alignment and simplified operation of a transmission electron microscope 52 (1993) 193
Williamson, R.L., C.J. Binks and M.J. Miles, Scanning tunnelling optical microscopy – breaking a resolution barrier? 57 (1995) 235
Wilshaw, P.R., see Konkol 55 (1994) 183
Wilshaw, P.R., see Konkol 58 (1995) 233
Winau, D., see Ichinokawa 54 (1994) 116
Winkler, D., see Alarco 51 (1993) 239
Winkler, H. and K.A. Taylor, 3D reconstruction by combining data from sections cut oblique to different unit cell axes 55 (1994) 357
Wolf, S.G., see Han 55 (1994) 1
Wong, K., see Egerton 59 (1995) 169
Wong, T.M.H., see O'Shea 52 (1993) 55
Wortmann, R., see Voigt-Martin 57 (1995) 29
Wu, I.-W., see Sinclair 51 (1993) 41

Xiao, H.Z. and A.C. Daykin, Extra diffractions caused by stacking faults in cubic crystals 53 (1994) 325
Xie, X.S., see Dunn 57 (1995) 113
Xie, X.S., see Dunn 57 (1995) 169
Xin, Y. and X.F. Duan, Reasonably good images of dislocations in LACBED patterns and effects of dislocation strain fields on the Bragg lines 53 (1994) 159
Xu, P., G. Jayaram and L.D. Marks, Cross-correlation method for intensity measurement of transmission electron diffraction patterns 53 (1994) 15
Xu, W., see Firtel 55 (1994) 113

Yagi, K., see Yamaguchi 52 (1993) 306
Yakobson, B.I. and M.A. Paesler, Tip optics for illumination NSOM: extended-zone approach 57 (1995) 204
Yakobson, B.I. and M.A. Paesler, Kinetics, morphology and pulling regimes for sensing tips in near-field microscopy 57 (1995) 241
Yamaguchi, H., T. Ohkawa and K. Yagi, Surface electromigration of metal atoms on modified Si(111) surfaces studied by REM 52 (1993) 306
Yamaguchi, T., see Yokota 54 (1994) 207
Yan, D.H., see Voigt-Martin 56 (1994) 271
Yan, D.H., see Voigt-Martin 57 (1995) 29
Yang, J.W., see Pirouz 51 (1993) 189
Yao, M.-H., D.J. Smith and A.K. Datye, Comparative study of supported catalyst particles by electron microscopy methods 52 (1993) 282
Yasuda, H., H. Mori and M. Maeda, UHVEM and AES analysis of electron-irradiation-induced gold-atom implantation into silicon carbide 56 (1994) 121
Yasunaga, T., see Tomokiyo 54 (1994) 276
Yokota, Y., H. Hashimoto and T. Yamaguchi, Electron beam irradiation of natural zeolites at low and room temperatures 54 (1994) 207
Young, S.J., see Fan 52 (1993) 499
Yuan, Z.W., S. Csillag, M.A. Tafreshi and C. Colliex, High spatial resolution extended energy loss fine structure investigations of silicon dioxide compounds 59 (1995) 149

Zaluzec, N.J., see Burgess 55 (1994) 276
Zaluzec, N.J., see Saunders 60 (1995) 311
Zandbergen, H.W., see Sheiko 53 (1994) 371
Zeitler, E., see Su 53 (1994) 97
Zeitler, E., see Uchida 55 (1994) 308
Zeitler, E., see Su 59 (1995) 181
Zhang, B., K.M. Krishnan and R.F.C. Farrow, Crystallography of Co/Pt multilayers and nanostructures 51 (1993) 298
Zhang, F.C., see Wang 59 (1995) 109
Zhang, H., see Wang 52 (1993) 523
Zhang, H., see Zhang 57 (1995) 103
Zhang, H., L.D. Marks, Y.Y. Wang, H. Zhang, V.P. Dravid, P. Han and D.A. Payne, Structure of planar defects in $(Sr_{0.9}Ca_{0.3})_{1.1}CuO_2$ infinite-layer superconductors by quantitative high-resolution electron microscopy 57 (1995) 103
Zhang, X., see Joy 51 (1993) 1
Zhang, X., D.C. Joy, Y.-S. Zhang, T. Hashimoto, L. Allard and T.A. Nolan, Electron holography techniques for study of ferroelectric domain walls 51 (1993) 21
Zhang, X., see Spence 55 (1994) 19
Zhang, X.B., X.F. Zhang, S. Amelinckx, G. Van Tendeloo and J. Van Landuyt, The reciprocal space of carbon tubes: a detailed interpretation of the electron diffraction effects 54 (1994) 237
Zhang, X.B., see Zhang 55 (1994) 25
Zhang, X.F., see Zhang 54 (1994) 237
Zhang, X.F., X.B. Zhang, D. Bernaerts, G. Van Tendeloo, S. Amelinckx, J. Van Landuyt and H. Werner, A simple preparation method of air-sensitive specimens for transmission electron microscopy demonstrated by Rb_6C_{60} 55 (1994) 25
Zhang, Y.-S., see Joy 51 (1993) 1
Zhang, Y.-S., see Zhang 51 (1993) 21
Zhao, Z.X., see Fu 54 (1994) 229
Zhu, Y. and Z.-X. Cai, Diffuse scattering and image contrast of tweed in superconducting oxides: simulation and interpretation 52 (1993) 539
Ziolkowski, R.W., see Kann 57 (1995) 251

Zou, X., Y. Sukharev and S. Hovmöller, Quantitative electron diffraction – new features in the program system ELD 52 (1993) 436
Zuo, J.M., New method of Bravais lattice determination 52 (1993) 459
Zuo, J.M., see Peng 57 (1995) 1
Zuo, J.M. and A.L. Weickenmeier, On the beam selection and convergence in the Bloch-wave method 57 (1995) 375
Zweck, J., see Bauer 51 (1993) 221
Zweck, J., see Schuhrke 58 (1995) 319

ELSEVIER

Ultramicroscopy 60 (1995) 467–484

ultramicroscopy

Subject index to volumes 51–60

Atomic force microscopy (AFM)
Influence of frictional forces on atomic force microscope images, *O'Shea, Welland and Wong* 52 (1993) 55
Force–displacement measurements in a beam-reflection scanning force microscope: calibration issues, *Haugstad and Gladfelter* 54 (1994) 31
Measurements of lateral distribution of fluorescence intensities and fluorescence spectra of microareas by a combined SNOM and AFM, *Fujihira, Monobe, Muramatsu and Ataka* 57 (1995) 118
Scanning near-field optic/atomic-force microscopy, *Muramatsu, Chiba, Ataka, Monobe and Fujihira* 57 (1995) 141
Near field plasmon and force microscopy, *De Hollander, Van Hulst and Kooyman* 57 (1995) 263
Problems in temperature control performing in situ investigations with the scanning force microscope, *Kipp, Lacmann and Schneeweiss* 57 (1995) 333
Immobilizing and imaging microtubules by atomic force microscopy, *Vinckier, Heyvaert, D'Hoore, McKittrick, Van Haesendonck, Engelborghs and Hellemans* 57 (1995) 337
Optimization of experiment in scanning force microscopy of polymers, *Wawkuschewski, Crämer, Cantow and Magonov* 58 (1995) 185
Use of a repositionable substrate to acquire and compare distinct atomic force microscope images of a field of microtubules, *Turner, Chang, Brandow, Murphy and Gaber* 58 (1995) 425
Wear of the atomic force microscope tip under light load, studied by atomic force microscopy, *Khurshudov and Kato* 60 (1995) 11
Imaging elastic sample properties with an atomic force microscope operating in the tapping mode, *Höper, Gesang, Possart, Hennemann and Boseck* 60 (1995) 17
Under buffer SFM observation of immunospecies adsorbed on a cyano grafted silicon substrate, *Mazeran, Loubet, Martelet and Theretz* 60 (1995) 33

Auger and secondary electron spectroscopy
Secondary electron coincidence detection and time of flight spectroscopy, *Müllejans, Bleloch, Howie and Tomita* 52 (1993) 360
Nanometer-resolution surface analysis with Auger electrons, *Liu, Hembree, Spinnler and Venables* 52 (1993) 369
Quantitative surface chemical mapping with Auger and backscattered electron signals, *Prutton, Barkshire and Crone* 59 (1995) 47

Book reviews
Tables, handbooks, proceedings and a life, *Hawkes* 52 (1993) 205
Volumes and issues, *Hawkes* 60 (1995) 325
Hawkes and Kasper, Volume 3, *Kruit* 60 (1995) 343

Contrast transfer theory
Selective imaging of sublattices in complex structures, *Amelinckx, Milat and Van Tendeloo* 51 (1993) 90
On effects of exit and entrance surface inclination on structure images, *Kim and Sheinin* 51 (1993) 109
Measuring the height of steps on MgO cubes using Fresnel contrast in a scanning transmission electron microscope, *Boothroyd and Humphreys* 52 (1993) 318
The defocus contrast of a θ' precipitate in Al–4wt%Cu: Fresnel fringe analysis applied to an atomically abrupt interface, *Dunin-Borkowski and Stobbs* 52 (1993) 404
High-resolution imaging of crystalline objects by hollow-cone illumination, *Dinges, Kohl and Rose* 55 (1994) 91
Partially coherent and holographic contrast transfer theory, *Marks and Plass* 55 (1994) 165
Theory and computation for imaging in scanning transmission microscopy considering partial coherence in illumination, *Gong* 55 (1994) 373
Breakdown of the weak-phase object approximation in amorphous objects and measurement of high-resolution electron optical parameters, *Gibson* 56 (1994) 26

Elsevier Science B.V.

The α-fringe contrast of thin twins in relation to the anomalous weak-beam contrast of stacking faults, *Chen and Stobbs* 58 (1995) 289
The problem of absorption in the Fresnel fringe analysis, *Schuhrke, Zweck and Hoffmann* 58 (1995) 319
Effect of three-fold astigmatism on high resolution electron micrographs, *Krivanek and Stadelmann* 60 (1995) 103
Ultimate resolution in the presence of coherence, *Van den Bos and Den Dekker* 60 (1995) 345

Convergent beam electron diffraction (CBED)

Local lattice parameter measurements in cyclically deformed copper by convergent-beam electron diffraction, *Maier, Renner and Mughrabi* 51 (1993) 136
New method of Bravais lattice determination, *Zuo* 52 (1993) 459
Reassessment of the symmetry of the 221 Pb-BiSrCaCuO structure using LACBED and high-resolution SAD: the relevance of Cowley's theory of disorder scattering to a real-space structural analysis, *Goodman and Miller* 52 (1993) 549
Observation of lattice fringes in convergent-beam electron diffraction patterns, *Terauchi, Tsuda, Kamimura, Tanaka, Kaneyama and Honda* 54 (1994) 268
Dynamical diffraction effect on HOLZ-pattern geometry in Si–Ge alloys and determination of local lattice parameter, *Tomokiyo, Matsumura, Okuyama, Yasunaga, Kuwano and Oki* 54 (1994) 276
LACBED determination of structure factors and alloy composition of GeSi/Si SLS, *Wang and Peng* 55 (1994) 67
Electron channelling effects at high incident angles in convergent beam reflection high energy electron diffraction, *Wang and Cowley* 55 (1994) 228
Observation of fourfold rotoinversion symmetry by convergent-beam electron diffraction, *Tanaka, Terauchi and Sato* 55 (1994) 241
Analytical filtering of low-angle inelastic scattering contributions to CBED contrast, *Marthinsen, Holmestad and Høier* 55 (1994) 268
Surface relaxation of strained heterostructures revealed by Bragg line splitting in LACBED patterns, *Chou, Anderson, Cockayne, Sikorski and Vaughan* 55 (1994) 334
Some notes on the selection of structural chirality by CBED, *Johnson and Preston* 55 (1994) 348
Strains in crystals with amorphous surface films studied by convergent beam electron diffraction and high-resolution imaging, *Banhart* 56 (1994) 233
Solving the crystal structure of a submicrometer phase in TEM, *Liu, Eades and Mazumder* 56 (1994) 253
On the beam selection and convergence in the Bloch-wave method, *Zuo and Weickenmeier* 57 (1995) 375
Incoherent contrast under dynamical diffraction conditions, *Rossouw* 58 (1995) 211
Observation of crystal distortions in SiGe/Si superlattice using a new application of large-angle convergent-beam electron diffraction, *Atici and Cherns* 58 (1995) 435
Energy-filtered convergent-beam diffraction: examples and future prospects, *Midgley, Saunders, Vincent and Steeds* 59 (1995) 1
Interferometry using convergent electron diffracted beams plus an electron biprism (CBED + EBI), *Herring, Pozzi, Tanji and Tonomura* 60 (1995) 153
Practical accuracy of grain misorientation measurements by Kikuchi line technique, *Gemperle and Gemperlová* 60 (1995) 207
Measurement of low-order structure factors for silicon from zone-axis CBED patterns, *Saunders, Bird, Zaluzec, Burgess, Preston and Humphreys* 60 (1995) 311

Cryomicroscopic methods

High-density morphologies of ice in high-pressure frozen biological specimens, *Richter* 53 (1994) 237
The ribosome at improved resolution: new techniques for merging and orientation refinement in 3D cryo-electron microscopy of biological particles, *Penczek, Grassucci and Frank* 53 (1994) 251
High-resolution electron microscopy of biological specimens in cubic ice, *Cyrklaff and Kühlbrandt* 55 (1994) 141
Analysis of transient structures by cryo-microscopy combined with rapid mixing of spray droplets, *Berriman and Unwin* 56 (1994) 241
Electron cryo-microscopy of graphite in amorphous ice, *Böttcher* 58 (1995) 417
Cryo-electron energy loss spectroscopy: observations on vitrified hydrated specimens and radiation damage, *Leapman and Sun* 59 (1995) 71

Data processing / image processing

Digital analysis of Young's interference fringes, *Ru* 55 (1994) 15
Density correction of photographic material for further image processing in electron microscopy, *Völkl, Lenz, Fu and Lichte* 55 (1994) 75
The use of maximum entropy and likelihood ranking to determine the crystal structure of 4-(4′-(N,N-dimethyl)aminobenzylidene)-pyrazolidine-3,5-dione at 1.4 Å resolution from electron diffraction and HREM image data, *Voigt-Martin, Yan, Gilmore, Shankland and Bricogne* 56 (1994) 271

Three-dimensional scatter diagrams: application to surface analytical microscopy, *Kenny, Barkshire and Prutton* 56 (1994) 289
Variable pitch in frozen-hydrated sickle hemoglobin fibers: an image analysis model study, *Lewis, Gross and Josephs* 56 (1994) 303
Preliminary investigation of two methods for the automatic handling of multivariate maps in microanalysis, *Bonnet* 57 (1995) 17
Proposal of alignment-independent classification of electron microscopic images with helical symmetry and its application to reconstituted thin filaments of skeletal muscle, *Ishikawa and Wakabayashi* 57 (1995) 91
Measurement of lattice-fringe vectors from digital HREM images: experimental precision, *De Ruijter, Sharma, McCartney and Smith* 57 (1995) 409
Advanced electron holography: a new algorithm for image processing and a standardized quality test for the FEG electron microscope, *Völkl, Allard, Datye and Frost* 58 (1995) 97
Determination of elastic strains in epitaxial layers by HREM, *Robertson, Currie, Corbett and Webb* 58 (1995) 175
Multiple least-squares fitting for quantitative electron energy-loss spectroscopy – an experimental investigation using standard specimens, *Door and Gängler* 58 (1995) 197
Automatic particle picking from electron micrographs, *Ramani Lata, Penczek and Frank* 58 (1995) 381
Erratum to "Preliminary investigation of two methods for the automatic handling of multivariate maps in microanalysis" [Ultramicroscopy 57 (1995) 17–27], *Bonnet* 58 (1995) 441
Analyzing line scan EELS data with neural pattern recognition, *Gatts, Duscher, Müllejans and Rühle* 59 (1995) 229
HREM alignment aided by a real-time diffractometer using a liquid-crystal panel, *Ishizuka and Chen* 60 (1995) 25
Improved methods for determination of rotational symmetries in macromolecules, *Kocsis, Cerritelli, Trus, Cheng and Steven* 60 (1995) 219
Crystallographic extraction and averaging of data from small image areas, *Perkins, Downing and Glaeser* 60 (1995) 283
Extension of the scatterplot approach to multiple images, *Bonnet, Herbin and Vautrot* 60 (1995) 349
Confidence limits for resolution estimation in image averaging by random subsampling, *De la Fraga, Dopazo and Carazo* 60 (1995) 385

Editorials, Announcements, Comments, Reports, Historical notes

Foreword, *Bradley and King* 51 (1993) vii
Foreword to Aspects of Electron Microscopy, Diffraction, Crystallography and Spectroscopy, *Smith and Spence* 52 (1993) vii
Preface to Festschrift for Professor Hashimoto, *Whelan* 54 (1994) 99
Foreword to Festschrift for Gunter Lehmpfuhl, *Goodman* 55 (1994) vii
Announcement: Comparison and test of HRTEM image simulation programs, *Van Dyck and Op de Beeck* 55 (1994) 435
Announcement 55 (1994) 438
Foreword to High-Voltage and High-Resolution Electron Microscopy, *Rühle, Phillipp, Seeger and Heydenreich* 56 (1994) ix
Letter to the Editor concerning Ultramicroscopy 53 (1994) 325–331, *Daykin* 56 (1994) xv
Editor's statement about co-authorship, *Kruit* 56 (1994) xvi
Reading matter, *Hawkes* 56 (1994) 337
Foreword to Near Field Optics, *Isaacson* 57 (1995) vii
Foreword to Microscopy with Field Emission Electron Sources, *Smith* 58 (1995) vii
Foreword to EELSI 94, *Krivanek and Stadelmann* 59 (1995) ix
Editorial, *Kruit* 60 (1995) v
Editorial, *Lindsay* 60 (1995) vi

Electron diffraction

Energy-filtered microdiffraction in a dedicated scanning transmission electron microscope, *Pike* 51 (1993) 117
Structures and phase transitions in C_{60} and C_{70} fullerites, *Van Tendeloo, Amelinckx, Muto, Verheijen, Van Loosdrecht and Meijer* 51 (1993) 168
Crystallography of Co/Pt multilayers and nanostructures, *Zhang, Krishnan and Farrow* 51 (1993) 298
Electron diffraction from gratings fabricated by electron beam nanolithography, *Ito, Bleloch, Paterson and Brown* 52 (1993) 347
Quantitative electron diffraction – new features in the program system ELD, *Zou, Sukharev and Hovmöller* 52 (1993) 436
High-resolution electron crystallography of protein molecules, *Glaeser and Downing* 52 (1993) 478
Quantitative imaging and diffraction of zeolites using a slow-scan CCD camera, *Pan and Crozier* 52 (1993) 487
Cross-correlation method for intensity measurement of transmission electron diffraction patterns, *Xu, Jayaram and Marks* 53 (1994) 15
Reasonably good images of dislocations in LACBED patterns and effects of dislocation strain fields on the Bragg lines, *Xin and Duan* 53 (1994) 159
Analysis of partial and stair-rod dislocations by large angle convergent beam electron diffraction, *Cherns and Morniroli* 53 (1994) 167
Kinematic analysis of transmission electron diffraction data from Si(111)-7 × 7, *Twesten and Gibson* 53 (1994) 223

Double conical beam-rocking system for measurement of integrated electron diffraction intensities, *Vincent and Midgley* 53 (1994) 271
Application of microdiffraction to crystal structure identification, *Redjaïmia and Morniroli* 53 (1994) 305
Energy filtering the "thermal diffuse" background in electron diffraction, *Eaglesham and Berger* 53 (1994) 319
Extra diffractions caused by stacking faults in cubic crystals, *Xiao and Daykin* 53 (1994) 325
Structures of carbon nanotubes studied by HRTEM and nanodiffraction, *Liu and Cowley* 53 (1994) 333
Determination of structure factors, lattice strains and accelerating voltage by energy-filtered convergent beam electron diffraction, *Deininger, Necker and Mayer* 54 (1994) 15
Quantitative evaluation of phasons in octogonal quasicrystals by high-resolution electron microscopy, *Jiang and Kuo* 54 (1994) 215
Incommensurate modulation in minute crystals revealed by combining high-resolution electron microscopy and electron diffraction, *Fu, Huang, Li, Li, Zhao, Cheng and Fan* 54 (1994) 229
The reciprocal space of carbon tubes: a detailed interpretation of the electron diffraction effects, *Zhang, Zhang, Amelinckx, Van Tendeloo and Van Landuyt* 54 (1994) 237
A report on speckle and coherent diffraction phenomena in selected-area transmission electron diffraction patterns, *Daykin* 55 (1994) 121
Electron diffraction of helical particles, *Ruiz, Ranck, Diaz-Avalos, Caspar and DeRosier* 55 (1994) 383
The use of maximum entropy and likelihood ranking to determine the crystal structure of 4-(4′-(N,N-dimethyl)aminobenzylidene)-pyrazolidine-3,5-dione at 1.4 Å resolution from electron diffraction and HREM image data, *Voigt-Martin, Yan, Gilmore, Shankland and Bricogne* 56 (1994) 271
Direct retrieval of crystal structure factors in THEED, *Peng and Zuo* 57 (1995) 1
The orthogonalized plane-wave method applied to the calculation of dynamical effects in electron diffraction, *Barreteau and Ducastelle* 57 (1995) 11
The use of simulation methods to obtain the structure and conformation of 10-cyano-9,9′-bianthryl by electron diffraction and high-resolution imaging, *Voigt-Martin, Yan, Wortmann and Elich* 57 (1995) 29
The Sayre equation in electron crystallography, *Dorset, Kopp, Fryer and Tivol* 57 (1995) 59
Studies of Mo/Si multilayers with coherent electron beams, *Gajdardziska-Josifovska, Weiss and Cowley* 58 (1995) 65
On the breakdown of Friedel's Law for coherent microdiffraction from amorphous materials, *Hÿtch and Chevalier* 58 (1995) 114
Momentum dependent energy loss near edge structures using a CTEM: the reliability of the methods available, *Botton, Boothroyd and Stobbs* 59 (1995) 93
Momentum-transfer resolved electron energy loss spectroscopy of solids: problems, solutions and applications, *Wang, Cheng, Dravid and Zhang* 59 (1995) 109
A simple and rapid method for determining orientations and misorientations of crystalline specimens in TEM, *Liu* 60 (1995) 81
Dynamical electron diffraction in substitutionally disordered column structures, *De Meulenaere, Van Dyck, Van Tendeloo and Van Landuyt* 60 (1995) 171
Top–bottom effects in double diffraction, *Tietz, Carter and McKernan* 60 (1995) 241
Diffuse scattering in electron diffraction data from protein crystals, *Grigorieff and Henderson* 60 (1995) 295

Electron diffraction and elastic scattering theory, image simulation

Practical aspects of electron holography, *Joy, Zhang, Zhang, Hashimoto, Bunn, Allard and Nolan* 51 (1993) 1
On effects of exit and entrance surface inclination on structure images, *Kim and Sheinin* 51 (1993) 109
Determination of thickness and defocus by quantitative comparison of experimental and simulated high-resolution images, *King and Campbell* 51 (1993) 128
Detection of substitutional atoms in a γ' phase by high-resolution electron microscopy, *Pénisson* 51 (1993) 264
HRTEM study of displacement cascade damage in krypton-ion-irradiated silicate – olivine, *Wang, Miller and Ewing* 51 (1993) 339
Coherence and multiple scattering in "Z-contrast" images, *Treacy and Gibson* 52 (1993) 31
A method for crystal potential retrieval in HRTEM, *Beeching and Spargo* 52 (1993) 243
Simulating the exit wave function for uniformly disordered systems, *Chevalier and Hytch* 52 (1993) 253
Spatial coherence effects in the use of high resolution approaches for the characterisation of the compositional abruptness of an interface, *Stobbs and Stobbs* 52 (1993) 267
Direct determination of crystal and surface structures in THEED, *Peng and Dudarev* 52 (1993) 312
Measuring the height of steps on MgO cubes using Fresnel contrast in a scanning transmission electron microscope, *Boothroyd and Humphreys* 52 (1993) 318
Thickness effects in ADF STEM zone axis images, *Hillyard and Silcox* 52 (1993) 325
Imaging elastic strains in high-angle annular dark field scanning transmission electron microscopy, *Perovic, Rossouw and Howie* 52 (1993) 353

Distorted wave approach to diffuse scattering in THEED and RHEED, *Dudarev, Peng and Whelan* 52 (1993) 393
Bloch wave symmetry in electron diffraction, *Gjønnes and Taftø* 52 (1993) 445
Thermal diffuse scattering in high-resolution electron holography, *Wang* 52 (1993) 504
Simulation of electron diffraction patterns from partially ordered layer lattices, *Treacy, Newsam and Deem* 52 (1993) 512
Diffuse scattering and image contrast of tweed in superconducting oxides: simulation and interpretation, *Zhu and Cai* 52 (1993) 539
Reassessment of the symmetry of the 221 Pb-BiSrCaCuO structure using LACBED and high-resolution SAD: the relevance of Cowley's theory of disorder scattering to a real-space structural analysis, *Goodman and Miller* 52 (1993) 549
Optimisation of high-resolution image simulations. II. Image selection in reciprocal space, *Tang, Kirkland and Jefferson* 53 (1994) 137
Quantitative comparison of high resolution TEM images with image simulations, *Hÿtch and Stobbs* 53 (1994) 191
An approach to the numerical solution of the problem of electron scattering in thin crystals, based on the Galerkin method, *Rukolaine* 54 (1994) 75
Erratum to "Coherence and multiple scattering in 'Z-contrast' images" [Ultramicroscopy 52 (1993) 31–53], *Treacy and Gibson* 54 (1994) 93
Multi-slice calculation for InP crystals using different slices, *Nishio, Isshiki, Saijo and Shiojiri* 54 (1994) 301
Non-local pseudopotentials in the multi-slice method of calculating electron wavefunctions in crystals, *Kambe and Stampfl* 55 (1994) 221
The effect of a non-Hermitian crystal potential on the scattering matrix in reflection electron diffraction, *Smith and Josefsson* 55 (1994) 247
Image formation by inelastically scattered electrons in TEM and STEM, *Fujimoto, Mazel and Sévely* 55 (1994) 253
Analytical filtering of low-angle inelastic scattering contributions to CBED contrast, *Marthinsen, Holmestad and Høier* 55 (1994) 268
Bloch-wave analysis of periodic surface contrast in zone-axis images, *Goodman, Matheson and Dong* 55 (1994) 314
Inversion of electron scattering intensity for crystal structure analysis, *Spargo, Beeching and Allen* 55 (1994) 329
On the mean inner potential in high- and low-energy electron diffraction, *Saldin and Spence* 55 (1994) 397
Announcement: Comparison and test of HRTEM image simulation programs, *Van Dyck and Op de Beeck* 55 (1994) 435
Detector geometry, thermal diffuse scattering and strain effects in ADF STEM imaging, *Hillyard and Silcox* 58 (1995) 6
Incoherent contrast under dynamical diffraction conditions, *Rossouw* 58 (1995) 211
Analysis of irradiated Ag and Si by molecular dynamics and simulated HREM images, *Mattei and Mazzone* 58 (1995) 223
The problem of absorption in the Fresnel fringe analysis, *Schuhrke, Zweck and Hoffmann* 58 (1995) 319
Simulation of TEM images considering phonon and electronic excitations, *Dinges, Berger and Rose* 60 (1995) 49
A useful approximation of the exit wave function in coherent STEM, *Broeckx, Op de Beeck and Van Dyck* 60 (1995) 71
Effect of three-fold astigmatism on high resolution electron micrographs, *Krivanek and Stadelmann* 60 (1995) 103
The relevance of dose-fractionation in tomography of radiation-sensitive specimens, *McEwen, Downing and Glaeser* 60 (1995) 357

Electron energy loss spectroscopy (EELS)

Low-dose thickness measurement of glucose-embedded protein crystals by electron energy loss spectroscopy and STEM dark-field imaging, *Leapman, Brink and Chiu* 52 (1993) 157
Electronic structure and dielectric function of oxide superconductors via transmission EELS with a cold field emission TEM, *Wang, Zhang and Dravid* 52 (1993) 523
Single-electron excitation of amorphous carbon observed with energy filter, *Su, Swoboda and Zeitler* 53 (1994) 97
The chromatic image shift in spatially resolved EELS, *Schattschneider, Jouffrey, Tischler and Bangert* 53 (1994) 181
Energy filtering the "thermal diffuse" background in electron diffraction, *Eaglesham and Berger* 53 (1994) 319
Improvements in detection sensitivity by spatial difference electron energy-loss spectroscopy at interfaces in ceramics, *Müllejans and Bruley* 53 (1994) 351
Spatial resolution in selected-area EELS, *Schenner and Schattschneider* 55 (1994) 31
Atomic ratios determined by EELS under parallel and convergent illumination conditions, *Su and Wang* 57 (1995) 323
EDS and EELS using a TEM-FEG microscope, *Stadelmann, Leifer and Verdon* 58 (1995) 35
PEELS compositional profiling and mapping at nanometer spatial resolution, *Tencé, Quartuccio and Colliex* 58 (1995) 42
Electron energy-loss chemical imaging of polymer phases, *Hunt, Disko, Behal and Leapman* 58 (1995) 55

Studies of Mo/Si multilayers with coherent electron beams, *Gajdardziska-Josifovska, Weiss and Cowley* 58 (1995) 65
Multiple least-squares fitting for quantitative electron energy-loss spectroscopy – an experimental investigation using standard specimens, *Door and Gängler* 58 (1995) 197
EXELFS as a tool for quantifying phase distributions in materials, *Haskel, Sarikaya, Qian and Stern* 58 (1995) 353
Conduction bandstructure in strained silicon by spatially resolved electron energy loss spectroscopy, *Batson* 59 (1995) 63
Cryo-electron energy loss spectroscopy: observations on vitrified hydrated specimens and radiation damage, *Leapman and Sun* 59 (1995) 71
Modelling the bonding at metal–ceramic interfaces using PEELS in the STEM, *Brydson, Bruley, Müllejans, Scheu and Rühle* 59 (1995) 81
Momentum dependent energy loss near edge structures using a CTEM: the reliability of the methods available, *Botton, Boothroyd and Stobbs* 59 (1995) 93
Momentum-transfer resolved electron energy loss spectroscopy of solids: problems, solutions and applications, *Wang, Cheng, Dravid and Zhang* 59 (1995) 109
Simulation of the extended fine structure of K-shell edges in intermetallic ordered alloys, *Hug, Blanche, Jaouen, Flank and Rehr* 59 (1995) 121
Development of the EXELFS technique for high accuracy structural information, *Qian, Sarikaya and Stern* 59 (1995) 137
High spatial resolution extended energy loss fine structure investigations of silicon dioxide compounds, *Yuan, Csillag, Tafreshi and Colliex* 59 (1995) 149
Some practical consequences of the Lorentzian angular distribution of inelastic scattering, *Egerton and Wong* 59 (1995) 169
The influence of plural scattering on EELS elemental analysis, *Su, Wang and Zeitler* 59 (1995) 181
The resolution limit for elemental mapping in energy-filtering transmission electron microscopy, *Kohl and Berger* 59 (1995) 191
A quantitative approach for spatially-resolved electron energy-loss spectroscopy of grain boundaries and planar defects on a subnanometer scale, *Gu, Čeh, Stemmer, Müllejans and Rühle* 59 (1995) 215
Analyzing line scan EELS data with neural pattern recognition, *Gatts, Duscher, Müllejans and Rühle* 59 (1995) 229
Progress in electron Compton scattering, *Schattschneider and Exner* 59 (1995) 241
Electron energy loss in multilayered slabs, *Bolton and Chen* 60 (1995) 247

Electron microscope design and characterization

Applications of a post-column imaging filter in biology and materials science, *Gubbens and Krivanek* 51 (1993) 146
Commercial spectrometer modifications for energy filtering of electron diffraction patterns and images, *Holmestad, Krivanek, Høier, Marthinsen and Spence* 52 (1993) 454
Experimental low-voltage point-projection microscopy and its possibilities, *Spence, Qian and Melmed* 52 (1993) 473
High-spatial-resolution analysis of Ge layers in Si, *Libera, Smith, Tsung and Eaglesham* 52 (1993) 564
0.1 nm information limit with the CM30FEG-Special Tübingen, *Lichte, Kessler, Lenz and Rau* 52 (1993) 575
Progress towards quantitative high-resolution electron microscopy, *Smith, De Ruijter, McCartney and Weiss* 52 (1993) 591
Double conical beam-rocking system for measurement of integrated electron diffraction intensities, *Vincent and Midgley* 53 (1994) 271
Aberration correction using off-axis holography. I. Aberration assessment, *Ishizuka, Tanji, Tonomura, Ohno and Murayama* 53 (1994) 361
Field emission ultrahigh-resolution analytical electron microscope, *Honda, Tomita, Kaneyama and Ishida* 54 (1994) 132
Characterization of an analytical electron microscope with a NiO test specimen, *Egerton and Cheng* 55 (1994) 43
Simulation of a Wien filter as beam separator in a low energy electron microscope, *Tsuno* 55 (1994) 127
Coma-free alignment of a high-resolution electron microscope with three-fold astigmatism, *Ishizuka* 55 (1994) 407
Three-fold astigmatism in high-resolution transmission electron microscopy, *Krivanek* 55 (1994) 419
New high-voltage atomic resolution microscope approaching 1 Å point resolution installed in Stuttgart, *Phillipp, Höschen, Osaki, Möbus and Rühle* 56 (1994) 1
Correction of aberrations, a promising means for improving the spatial and energy resolution of energy-filtering electron microscopes, *Rose* 56 (1994) 11
Breakdown of the weak-phase object approximation in amorphous objects and measurement of high-resolution electron optical parameters, *Gibson* 56 (1994) 26
Instrumental factors in high-resolution FEG STEM, *Von Harrach* 58 (1995) 1
Simple prescriptions for estimating three-fold astigmatism, *Saxton* 58 (1995) 239
Measurement of TEM primary energy with an electron energy-loss spectrometer, *Meyer, Boothroyd, Gubbens and Krivanek* 59 (1995) 283

Analysis of sensitivity of cold stages on Philips CM12 to sources of vibration, *Henderson and Faruqi* 60 (1995) 375

Electron sources

HV TEM in situ investigations of the tip shape of a gallium liquid-metal ion/electron emitter, *Driesel, Dietzsch, Niedrig and Praprotnik* 57 (1995) 45

Energy-filtered imaging and diffraction

Energy-filtered microdiffraction in a dedicated scanning transmission electron microscope, *Pike* 51 (1993) 117

Applications of a post-column imaging filter in biology and materials science, *Gubbens and Krivanek* 51 (1993) 146

Commercial spectrometer modifications for energy filtering of electron diffraction patterns and images, *Holmestad, Krivanek, Høier, Marthinsen and Spence* 52 (1993) 454

Determination of structure factors, lattice strains and accelerating voltage by energy-filtered convergent beam electron diffraction, *Deininger, Necker and Mayer* 54 (1994) 15

Atomic resolution electron microscope images formed by Si L_3-ionization electrons, *Endoh and Hashimoto* 54 (1994) 351

Detection limits in elemental distribution images produced by energy filtering TEM: case study of grain boundaries in Si_3N_4, *Berger, Mayer and Kohl* 55 (1994) 101

Benefits of energy filtering for advanced convergent beam electron diffraction patterns, *Burgess, Preston, Botton, Zaluzec and Humphreys* 55 (1994) 276

Theoretical and observed electron microscope images of impurity atoms in thin crystals formed by L-shell ionization electrons, *Endoh, Hashimoto and Makita* 56 (1994) 108

Quantitative elemental mapping of materials by energy-filtered imaging, *Crozier* 58 (1995) 157

Energy-filtered convergent-beam diffraction: examples and future prospects, *Midgley, Saunders, Vincent and Steeds* 59 (1995) 1

Imaging of nanometer-sized precipitates in solids by electron spectroscopic imaging, *Hofer, Warbichler and Grogger* 59 (1995) 15

Energy-filtered transmission electron microscopy of Si_mGe_n superlattices and Si–Ge heterostructures. I. Experimental results, *Jäger and Mayer* 59 (1995) 33

The resolution limit for elemental mapping in energy-filtering transmission electron microscopy, *Kohl and Berger* 59 (1995) 191

Energy-filtering and composition-sensitive imaging in surface and interface studies using HREM, *Wang and Shapiro* 60 (1995) 115

Exit wave reconstruction

Error analysis of crystalline ptychography in the STEM mode, *McCallum and Rodenburg* 52 (1993) 85

A method for crystal potential retrieval in HRTEM, *Beeching and Spargo* 52 (1993) 243

Resolution improvement by tilted single-sideband holography: preliminary experiments, *Ishizuka* 53 (1994) 9

Non-linear reconstruction of the exit plane wave function from periodic high-resolution electron microscopy images, *Thust, Lentzen and Urban* 53 (1994) 101

Number of sampling points required for aberration correction using off-axis electron holography, *Ishizuka* 53 (1994) 297

Aberration correction using off-axis holography. I. Aberration assessment, *Ishizuka, Tanji, Tonomura, Ohno and Murayama* 53 (1994) 361

Beyond the conventional information limit: the relevant coherence function, *Nellist and Rodenburg* 54 (1994) 61

Incommensurate modulation in minute crystals revealed by combining high-resolution electron microscopy and electron diffraction, *Fu, Huang, Li, Li, Zhao, Cheng and Fan* 54 (1994) 229

Spherical-aberration-free observation of profile images of the Au(011) surface by defocus-modulation image processing, *Takai, Taniguchi, Ikuta and Shimizu* 54 (1994) 250

Development of real-time defocus-modulation-type active image processing (DMAIP) for spherical-aberration-free TEM observation, *Ando, Taniguchi, Takai, Kimura, Shimizu and Ikuta* 54 (1994) 261

High-resolution electron holography with the CM30FEG-Special Tübingen, *Lichte and Rau* 54 (1994) 310

What is the focus variation method? Is it new? Is it direct?, *Saxton* 55 (1994) 171

Aberration correction using off-axis holography. II. Beyond the Scherzer limit, *Ishizuka, Tanji, Tonomura, Ohno and Murayama* 55 (1994) 197

Premise-free reconstruction of the exit-surface wave function in HRTEM, *Bierwolf and Hohenstein* 56 (1994) 32

Super-resolution by aperture synthesis: tilt series reconstruction in CTEM, *Kirkland, Saxton, Chau, Tsuno and Kawasaki* 57 (1995) 355

High resolution transmission electron microscopy (HRTEM)

In situ HRTEM study of Ω precipitate dissolution in an Al–Cu–Mg–Ag alloy, *Chang and Howe* 51 (1993) 46

Selective imaging of sublattices in complex structures, *Amelinckx, Milat and Van Tendeloo* 51 (1993) 90

On effects of exit and entrance surface inclination on structure images, *Kim and Sheinin* 51 (1993) 109
Determination of thickness and defocus by quantitative comparison of experimental and simulated high-resolution images, *King and Campbell* 51 (1993) 128
Structures and phase transitions in C_{60} and C_{70} fullerites, *Van Tendeloo, Amelinckx, Muto, Verheijen, Van Loosdrecht and Meijer* 51 (1993) 168
Misfit dislocations in epitaxial ZnTe/GaAs (001) studied by HRTEM, *Bauer, Rosenauer, Link, Kuhn, Zweck and Gebhardt* 51 (1993) 221
90° boundaries and associated interfacial and stand-off partial dislocations in $YBa_2Cu_3O_{7-x}$, *Carim and Mitchell* 51 (1993) 228
High-resolution electron microscopy investigation of the (710) twin in Nb, *Campbell, Wien, King, Foiles and Rühle* 51 (1993) 247
Detection of substitutional atoms in a γ' phase by high-resolution electron microscopy, *Pénisson* 51 (1993) 264
HRTEM study of atomic faceting of asymmetrical twin and asymmetrical hetero-twin boundaries in $NiSi_2$/Si, *Chen and Chen* 51 (1993) 316
HRTEM study of displacement cascade damage in krypton-ion-irradiated silicate – olivine, *Wang, Miller and Ewing* 51 (1993) 339
Analysis of power spectra of high resolution electron micrographs, *Anstis, Auchterlonie and Barry* 52 (1993) 167
Quantitative method of assessing the nature of local order from HREM images for SRO on crystalline sublattices, *Hytch and Chevalier* 52 (1993) 415
New complex structures in the cesium–niobium–tungsten–oxide system revealed by HREM, *Lundberg and Sundberg* 52 (1993) 429
Progress towards quantitative high-resolution electron microscopy, *Smith, De Ruijter, McCartney and Weiss* 52 (1993) 591
Comparison of the information content in ⟨110⟩- and ⟨100⟩-projected high-resolution transmission electron microscope images for the quantitative analysis of AlAs/GaAs interfaces, *Thoma and Cerva* 53 (1994) 37
Combination of high-resolution electron imaging and holography in the investigation of the modulated structure of $Zr_4ON_3F_5$, *Schweda, Strähle, Lichte and Völkl* 53 (1994) 53
The use of non-linear characteristics of a lattice fringe image for the characterisation of imaging parameters, *Hÿtch and Stobbs* 53 (1994) 63
HREM of Ga_2Te_3: imaging of an ordered vacancy superlattice with enhanced contrast, *Hutchison, Chou, Casanove, Cherns, Steeds, Asherford and Lunn* 53 (1994) 91
Quantitative comparison of high resolution TEM images with image simulations, *Hÿtch and Stobbs* 53 (1994) 191
Quantitative high-resolution transmission electron microscopy of the incoherent $\Sigma 3$ (211) boundary in Cu, *Hofmann and Ernst* 53 (1994) 205
Erratum to "Combination of high-resolution electron imaging and holography in the investigation of the modulated structure of $Zr_4ON_3F_5$" [Ultramicroscopy 53 (1994) 53–62], *Schweda, Strähle, Lichte and Völkl* 54 (1994) 94
Investigation of atomic structure of ω-phase crystals in Ti–Mo alloys using high-resolution electron microscopy, *Sukedai, Liu, Awaji and Horiuchi* 54 (1994) 192
Quantitative evaluation of phasons in octogonal quasicrystals by high-resolution electron microscopy, *Jiang and Kuo* 54 (1994) 215
Quantitative high-resolution electron microscopy of a high-T_c superconductor $Tl_2Ba_2Cu_1O_y$ with the imaging plate, *Shindo, Oku, Kudoh and Oikawa* 54 (1994) 221
Incommensurate modulation in minute crystals revealed by combining high-resolution electron microscopy and electron diffraction, *Fu, Huang, Li, Li, Zhao, Cheng and Fan* 54 (1994) 229
Quantitative HREM using non-linear least-squares methods, *King and Campbell* 56 (1994) 46
Structure determination of metal–ceramic interfaces by numerical contrast evaluation of HRTEM micrographs, *Möbus and Rühle* 56 (1994) 54
Determination of grain boundary volume expansion by HREM, *Buckett and Merkle* 56 (1994) 71
High-resolution transmission electron microscopy studies of dislocation cores in metals and intermetallic compounds, *Mills, Daw and Foiles* 56 (1994) 79
Strains in crystals with amorphous surface films studied by convergent beam electron diffraction and high-resolution imaging, *Banhart* 56 (1994) 233
Solving the crystal structure of a submicrometer phase in TEM, *Liu, Eades and Mazumder* 56 (1994) 253
The use of maximum entropy and likelihood ranking to determine the crystal structure of 4-(4′-(N,N-dimethyl)aminobenzylidene)-pyrazolidine-3,5-dione at 1.4 Å resolution from electron diffraction and HREM image data, *Voigt-Martin, Yan, Gilmore, Shankland and Bricogne* 56 (1994) 271
The use of simulation methods to obtain the structure and conformation of 10-cyano-9,9′-bianthryl by electron diffraction and high-resolution imaging, *Voigt-Martin, Yan, Wortmann and Elich* 57 (1995) 29
Structure of planar defects in $(Sr_{0.9}Ca_{0.3})_{1.1}CuO_2$ infinite-layer superconductors by quantitative high-resolution electron microscopy, *Zhang, Marks, Wang, Zhang, Dravid, Han and Payne* 57 (1995) 103
Measurement of lattice-fringe vectors from dig-

ital HREM images: experimental precision, *De Ruijter, Sharma, McCartney and Smith* 57 (1995) 409
An approach to quantitative high-resolution transmission electron microscopy of crystalline materials, *Kisielowski, Schwander, Baumann, Seibt, Kim and Ourmazd* 58 (1995) 131
Determination of elastic strains in epitaxial layers by HREM, *Robertson, Currie, Corbett and Webb* 58 (1995) 175
The HREM use of the FEGTEM for the study of interfaces, *Stobbs, Sato and Stobbs* 58 (1995) 275
The consequences of the atomic size effect in quantitative high resolution electron microscopy, *Glas* 60 (1995) 91
On the interpretation of HREM images of partially ordered alloys, *De Meulenaere, Van Tendeloo, Van Landuyt and Van Dyck* 60 (1995) 265
Ultimate resolution in the presence of coherence, *Van den Bos and Den Dekker* 60 (1995) 345

High voltage electron microscopy (HVEM)
Topics in in-situ experiments in the HVEM, *Mori, Komatsu and Fujita* 51 (1993) 31
Quantitative high-resolution transmission electron microscopy of the incoherent $\Sigma 3$ (211) boundary in Cu, *Hofmann and Ernst* 53 (1994) 205
Electron-diffraction channeling effect on defect formation in Si with ⟨110⟩ zone-axis incidence, *Takeda and Horiuchi* 56 (1994) 144

Holography
Practical aspects of electron holography, *Joy, Zhang, Zhang, Hashimoto, Bunn, Allard and Nolan* 51 (1993) 1
Parameters for high-resolution electron holography, *Lichte* 51 (1993) 15
Electron holography techniques for study of ferroelectric domain walls, *Zhang, Joy, Zhang, Hashimoto, Allard and Nolan* 51 (1993) 21
Optimized sampling schemes for off-axis holography, *Ishizuka* 52 (1993) 1
Deconvolving lens transfer functions in electron holograms, *Kawasaki and Rodenburg* 52 (1993) 248
Experimental low-voltage point-projection microscopy and its possibilities, *Spence, Qian and Melmed* 52 (1993) 473
Thermal diffuse scattering in high-resolution electron holography, *Wang* 52 (1993) 504
0.1 nm information limit with the CM30FEG-Special Tübingen, *Lichte, Kessler, Lenz and Rau* 52 (1993) 575
Electron holography available in a non-biprism transmission electron microscope, *Ru, Osakabe, Endo and Tonomura* 53 (1994) 1
Resolution improvement by tilted single-sideband holography: preliminary experiments, *Ishizuka* 53 (1994) 9
On electron holographic mapping of electric and magnetic fields: recording and processing problems and field information reliability, *Matteucci and Muccini* 53 (1994) 19
Combination of high-resolution electron imaging and holography in the investigation of the modulated structure of $Zr_4ON_3F_5$, *Schweda, Strähle, Lichte and Völkl* 53 (1994) 53
Absolute measurement of normalized thickness, t/λ_i, from off-axis electron holography, *McCartney and Gajdardziska-Josifovska* 53 (1994) 283
Elimination of thickness dependence from medium resolution electron holograms, *Gajdardziska-Josifovska and McCartney* 53 (1994) 291
Number of sampling points required for aberration correction using off-axis electron holography, *Ishizuka* 53 (1994) 297
Aberration correction using off-axis holography. I. Aberration assessment, *Ishizuka, Tanji, Tonomura, Ohno and Murayama* 53 (1994) 361
Dynamic observation of magnetic domains by on-line real-time electron holography, *Hirayama, Chen, Tanji and Tonomura* 54 (1994) 9
Erratum to "Combination of high-resolution electron imaging and holography in the investigation of the modulated structure of $Zr_4ON_3F_5$" [Ultramicroscopy 53 (1994) 53–62], *Schweda, Strähle, Lichte and Völkl* 54 (1994) 94
High-resolution electron holography with the CM30FEG-Special Tübingen, *Lichte and Rau* 54 (1994) 310
Phase-contrast visualization of an undecagold cluster by in-line electron holography, *Matsumoto, Tanji and Tonomura* 54 (1994) 317
Reconstruction of electron off-axis holograms: a new and fast alternative method, *Lehmann, Völkl and Lenz* 54 (1994) 335
A report on speckle and coherent diffraction phenomena in selected-area transmission electron diffraction patterns, *Daykin* 55 (1994) 121
Aberration correction using off-axis holography. II. Beyond the Scherzer limit, *Ishizuka, Tanji, Tonomura, Ohno and Murayama* 55 (1994) 197
Principle and application of phase-shifting electron holography, *Ru, Lai, Aoyama, Endo and Tonomura* 55 (1994) 209
Chromatic coherence and inelastic scattering in electron holography, *Cowley* 57 (1995) 327
Simulation of electron holographic contour maps of linear charged dislocations, *Cavalcoli, Matteucci and Muccini* 57 (1995) 385
Interpretable resolution of 0.2 nm at 100 kV using electron holography, *Harscher, Lang and Lichte* 58 (1995) 79
Far-out-of-focus electron holography in a dedicated FEG STEM, *Mankos, Higgs, Scheinfein and Cowley* 58 (1995) 87

Advanced electron holography: a new algorithm for image processing and a standardized quality test for the FEG electron microscope, *Völkl, Allard, Datye and Frost* 58 (1995) 97
Interferometry using convergent electron diffracted beams plus an electron biprism (CBED + EBI), *Herring, Pozzi, Tanji and Tonomura* 60 (1995) 153

Image detectors

Analysis of electron image detection efficiency of slow-scan CCD cameras, *Ishizuka* 52 (1993) 7
High-sensitivity lens-coupled slow-scan CCD camera for transmission electron microscopy, *Fan and Ellisman* 52 (1993) 21
A versatile, software configurable multichannel STEM detector for angle-resolved imaging, *Haider, Epstein, Jarron and Boulin* 54 (1994) 41
Intensity distribution of scintillation produced by high-energy electrons, *Kamiya, Michishita and Tanaka* 54 (1994) 286
Computer simulation of light emission by high-energy electrons in YAG single crystals, *Kotera and Kamiya* 54 (1994) 293
Performance of thin foil scintillating screen for transmission electron microscopy, *Fan, Dunkelberger and Ellisman* 55 (1994) 7
A new quasi-confocal image plate scanner with improved spatial resolution and ideal detection efficiency, *Burmester, Braun and Schröder* 55 (1994) 55
Density correction of photographic material for further image processing in electron microscopy, *Völkl, Lenz, Fu and Lichte* 55 (1994) 75
Detector geometry, thermal diffuse scattering and strain effects in ADF STEM imaging, *Hillyard and Silcox* 58 (1995) 6
Optimum rotationally symmetric detector configurations for phase-contrast imaging in scanning transmission electron microscopy, *Hammel and Rose* 58 (1995) 403

Impact phenomena: Auger, X-ray and secondary electron emission, radiation effects

Parallel simulation of electron–solid interactions: a rapid aid for electron microscope data interpretation, *Michael, Plimpton and Romig, Jr.* 51 (1993) 160
Secondary electron coincidence detection and time of flight spectroscopy, *Müllejans, Bleloch, Howie and Tomita* 52 (1993) 360
Correlations between ionization radiation damage and charging effects in transmission electron microscopy, *Cazaux* 60 (1995) 411

In situ specimen treatment

Topics in in-situ experiments in the HVEM, *Mori, Komatsu and Fujita* 51 (1993) 31
Direct observation of crystallization in silicon by in situ high-resolution electron microscopy, *Sinclair, Morgiel, Kirtikar, Wu and Chiang* 51 (1993) 41
In situ HRTEM study of Ω precipitate dissolution in an Al–Cu–Mg–Ag alloy, *Chang and Howe* 51 (1993) 46
In-situ dynamic processes on cleaved α-alumina bulk crystal surfaces imaged by reflection electron microscopy, *Wang and Bentley* 51 (1993) 64
Edge instabilities in thin plates studied by in situ transmission electron microscopy, *Hackney, Lillo, Kedia, Horn and Plichta* 51 (1993) 81
In situ domain multiplication and migration in the antiferroelectric ceramic PLSnZT, *De Graef, Clarke and Speck* 52 (1993) 179
HREM observations of the conversion of β-Sn into $PtSn_4$ in the Pt–Sn thin film system, *Dufner* 52 (1993) 276
Analysis of time-resolved, in-situ change in high-resolution electron microscopy, *Kang and Eyring* 52 (1993) 377
The effect of an electric field on the crystallization of gel-derived alumina precursors observed in situ in the TEM, *Tong, Wheatley and Eyring* 52 (1993) 388
In-situ dynamic high-resolution transmission electron microcopy: application to Pt/GaAs interfacial reactions, *Ko and Sinclair* 54 (1994) 166
High-temperature straining stage for in situ experiments in the high-voltage electron microscope, *Messerschmidt and Bartsch* 56 (1994) 163
On the extraction of high quality data from real-time transmission electron microscopy experiments, *Bithell, Doole and Goringe* 56 (1994) 172
In-situ transmission electron microscopy of grain boundaries in $CuGa_2$, *Sasaki, Murase and Saka* 56 (1994) 184
Defect-flow-induced grain boundary migration with segregation under electron irradiation, *Takahashi, Hashimoto and Watanabe* 56 (1994) 193
In situ ion- and electron-irradiation effects studies in transmission electron microscopes, *Allen* 56 (1994) 200
In-situ observations of irradiation-induced phase transformations, *Kinoshita, Tomokiyo and Nakai* 56 (1994) 216
In situ HREM: application to metal-mediated crystallization, *Sinclair and Konno* 56 (1994) 225

Inelastic electron scattering theory

Parallel simulation of electron–solid interactions: a rapid aid for electron microscope data interpretation, *Michael, Plimpton and Romig, Jr.* 51 (1993) 160
Does phonon scattering give high-resolution images?, *Rez* 52 (1993) 260

Single-electron excitation of amorphous carbon observed with energy filter, *Su, Swoboda and Zeitler* 53 (1994) 97
Energy filtering the "thermal diffuse" background in electron diffraction, *Eaglesham and Berger* 53 (1994) 319
Atomic and electronic Z-contrast effects in high-resolution imaging, *Bleloch, Castell, Howie and Walsh* 54 (1994) 107
Atomic resolution electron microscope images formed by Si L_3-ionization electrons, *Endoh and Hashimoto* 54 (1994) 351
Image formation by inelastically scattered electrons in TEM and STEM, *Fujimoto, Mazel and Sévely* 55 (1994) 253
Interaction delocalization in characteristic X-ray emission from light elements, *Allen, Josefsson and Rossouw* 55 (1994) 258
Chromatic coherence and inelastic scattering in electron holography, *Cowley* 57 (1995) 327
General formulation for ALCHEMI, *Horita, Matsumura and Baba* 58 (1995) 327
Simulation of the extended fine structure of K-shell edges in intermetallic ordered alloys, *Hug, Blanche, Jaouen, Flank and Rehr* 59 (1995) 121
Review of methods for calculating near edge structure, *Rez, Bruley, Brohan, Payne and Garvie* 59 (1995) 159
Some practical consequences of the Lorentzian angular distribution of inelastic scattering, *Egerton and Wong* 59 (1995) 169
Delocalization in inelastic scattering, *Muller and Silcox* 59 (1995) 195
Progress in electron Compton scattering, *Schattschneider and Exner* 59 (1995) 241
Simulation of TEM images considering phonon and electronic excitations, *Dinges, Berger and Rose* 60 (1995) 49

Instrument control and alignment

A simple concept for better alignment and simplified operation of a transmission electron microscope, *Wilbrandt* 52 (1993) 193
Telemicroscopy, *Fan, Mercurio, Young and Ellisman* 52 (1993) 499
The use of non-linear characteristics of a lattice fringe image for the characterisation of imaging parameters, *Hÿtch and Stobbs* 53 (1994) 63
The chromatic image shift in spatially resolved EELS, *Schattschneider, Jouffrey, Tischler and Bangert* 53 (1994) 181
Digital analysis of Young's interference fringes, *Ru* 55 (1994) 15
Coma-free alignment of a high-resolution electron microscope with three-fold astigmatism, *Ishizuka* 55 (1994) 407
Three-fold astigmatism in high-resolution transmission electron microscopy, *Krivanek* 55 (1994) 419
Simple prescriptions for estimating three-fold astigmatism, *Saxton* 58 (1995) 239
HREM alignment aided by a real-time diffractometer using a liquid-crystal panel, *Ishizuka and Chen* 60 (1995) 25
A simple and rapid method for determining orientations and misorientations of crystalline specimens in TEM, *Liu* 60 (1995) 81

Low energy electron microscopy and diffraction (LEEM and LEED)

Contrast and radiation damage in point-projection electron imaging of purple membrane at 100 V, *Spence, Qian and Zhang* 55 (1994) 19
Nanometric observations at low energy by Fresnel projection microscopy: carbon and polymer fibres, *Vu Thien Binh, Semet and Garcia* 58 (1995) 307

Microscopic methods, specifically for biological specimens

Low-dose thickness measurement of glucose-embedded protein crystals by electron energy loss spectroscopy and STEM dark-field imaging, *Leapman, Brink and Chiu* 52 (1993) 157
Electron diffraction of helical particles, *Ruiz, Ranck, Diaz-Avalos, Caspar and DeRosier* 55 (1994) 383
Variable pitch in frozen-hydrated sickle hemoglobin fibers: an image analysis model study, *Lewis, Gross and Josephs* 56 (1994) 303
Proposal of alignment-independent classification of electron microscopic images with helical symmetry and its application to reconstituted thin filaments of skeletal muscle, *Ishikawa and Wakabayashi* 57 (1995) 91
PHOELIX: a package for semi-automated helical reconstruction, *Whittaker, Carragher and Milligan* 58 (1995) 245
Quantitative evaluation of heavy metal decoration on protein molecules: contrast, specificity and resolution, *Rübenkamm, Braun, Bachmann, Bacher, Brandt, Baumeister and Weinkauf* 58 (1995) 337
Automatic particle picking from electron micrographs, *Ramani Lata, Penczek and Frank* 58 (1995) 381
Improved methods for determination of rotational symmetries in macromolecules, *Kocsis, Cerritelli, Trus, Cheng and Steven* 60 (1995) 219

Microscopic methods, specifically for catalysts and small particles

The effect of adsorbate and pretreatment on the shape and reactivity of silica-supported platinum particles, *Ramachandran, Anderson and Datye* 51 (1993) 282
Comparative study of supported catalyst particles by electron microscopy methods, *Yao, Smith and Datye* 52 (1993) 282

Direct observation of epitaxially grown C_{60} crystals and molecules on vacuum-deposited MgO films, *Tanaka, Kitagawa, Kachi and Kizuka* 52 (1993) 533
Investigation of heterogeneous $Cu_{1-x}Co_x$ alloys with giant magnetoresistance, *Hütten and Thomas* 52 (1993) 581
Structures of carbon nanotubes studied by HRTEM and nanodiffraction, *Liu and Cowley* 53 (1994) 333
Growth of dendritic and needle tungsten oxide crystals studied by high-resolution electron microscopy, *Kumao, Fujita and Endoh* 54 (1994) 201
Interpretation of the {100} fringes in lattice images from the centre of carbon nanotubes, *Cullen, Boothroyd and Humphreys* 56 (1994) 127
Imaging of nanometer-sized precipitates in solids by electron spectroscopic imaging, *Hofer, Warbichler and Grogger* 59 (1995) 15
A simple and rapid method for determining orientations and misorientations of crystalline specimens in TEM, *Liu* 60 (1995) 81
Practical accuracy of grain misorientation measurements by Kikuchi line technique, *Gemperle and Gemperlová* 60 (1995) 207

Microscopic methods, specifically for solid interfaces and multilayers

Direct observation of crystallization in silicon by in situ high-resolution electron microscopy, *Sinclair, Morgiel, Kirtikar, Wu and Chiang* 51 (1993) 41
Polytypic transformations in SiC: the role of TEM, *Pirouz and Yang* 51 (1993) 189
Contradictory increase of critical layer thickness in $In_xGa_{1-x}Sb/GaAs$ heterostructures grown by MBE, *Olsson, Ekenstedt, Wang, Qu and Andersson* 51 (1993) 215
Misfit dislocations in epitaxial ZnTe/GaAs (001) studied by HRTEM, *Bauer, Rosenauer, Link, Kuhn, Zweck and Gebhardt* 51 (1993) 221
90° boundaries and associated interfacial and stand-off partial dislocations in $YBa_2Cu_3O_{7-x}$, *Carim and Mitchell* 51 (1993) 228
Microstructure of an artificial grain boundary weak link in an $YBa_2Cu_3O_{7-\delta}$ thin film grown on a (100)(110), [001]-tilt $Y–ZrO_2$ bicrystal, *Alarco, Olsson, Ivanov, Nilsson, Winkler, Stepantsov and Tzalenchuk* 51 (1993) 239
High-resolution electron microscopy investigation of the (710) twin in Nb, *Campbell, Wien, King, Foiles and Rühle* 51 (1993) 247
Structural ledges at precipitate/matrix interfaces in a (Ni, Co) superalloy: atomic structures and elastic fields, *Loubradou, Pénisson and Bonnet* 51 (1993) 270
Crystallography of Co/Pt multilayers and nanostructures, *Zhang, Krishnan and Farrow* 51 (1993) 298
Cross-sectional transmission electron microscopy studies of metallic multilayers, *De Veirman, Hakkens and Dirks* 51 (1993) 306
HRTEM study of atomic faceting of asymmetrical twin and asymmetrical hetero-twin boundaries in $NiSi_2/Si$, *Chen and Chen* 51 (1993) 316
Electron microscopy of the grain structure of metal films and lines, *Smith, Small and Stanis* 51 (1993) 328
Thin film Ti/6H-SiC interfacial reaction: high spatial resolution electron microscopy study, *Bow, Porter, Kim, Carpenter and Davis* 52 (1993) 289
The defocus contrast of a θ' precipitate in Al–4wt%Cu: Fresnel fringe analysis applied to an atomically abrupt interface, *Dunin-Borkowski and Stobbs* 52 (1993) 404
A high-resolution electron microscopy study of vanadium deposited on the basal plane of sapphire, *Ikuhara and Pirouz* 52 (1993) 421
Modulated structures in the Cu–Au and (CuAu)–Ag alloys with antiphase structures of CuAu(II) type, *Watanabe, Ohsuna and Kimoto* 52 (1993) 465
Atomic structure of undoped $\Sigma = 5$ symmetrical tilt grain boundary in strontium titanate, *Ravikumar and Dravid* 52 (1993) 557
High-spatial-resolution analysis of Ge layers in Si, *Libera, Smith, Tsung and Eaglesham* 52 (1993) 564
Arsenic implantation into GaAs: a SOI technology for compound semiconductors?, *Liliental-Weber, Namavar and Claverie* 52 (1993) 570
Comparison of the information content in ⟨110⟩- and ⟨100⟩-projected high-resolution transmission electron microscope images for the quantitative analysis of AlAs/GaAs interfaces, *Thoma and Cerva* 53 (1994) 37
High-resolution transmission electron microscopy investigation of interfaces in metal–silicon systems, *Chen, Liang, Liu, Hsieh, Lin, Lee, Wang and Chen* 54 (1994) 156
In-situ dynamic high-resolution transmission electron microcopy: application to Pt/GaAs interfacial reactions, *Ko and Sinclair* 54 (1994) 166
High-resolution electron microscopy of Cu/MgO and Pd/MgO interfaces, *Chen, Chiou, Chang and Hong* 54 (1994) 179
Reflection electron microscopy of buried interfaces in the transmission geometry, *Spence* 55 (1994) 293
Structure determination of metal–ceramic interfaces by numerical contrast evaluation of HRTEM micrographs, *Möbus and Rühle* 56 (1994) 54
Determination of grain boundary volume expansion by HREM, *Buckett and Merkle* 56 (1994) 71
Quantitative analysis of the deformation and chemical profiles of strained multilayers, *Bayle, Deutsch, Gilles, Lançon, Marty and Thibault* 56 (1994) 94
On the role of dislocations in heavily strained $YBa_2Cu_3O_{7-\delta}$, *Verwerft, Dijken, De Hosson and Van der Steen* 56 (1994) 135

Studies of Mo/Si multilayers with coherent electron beams, *Gajdardziska-Josifovska, Weiss and Cowley* 58 (1995) 65
Field-emission SEM imaging of compositional and doping layer semiconductor superlattices, *Perovic, Castell, Howie, Lavoie, Tiedje and Cole* 58 (1995) 104
Backscattered electron contrast on cross sections of interfaces and multilayers in the scanning electron microscope, *Konkol, Booker and Wilshaw* 58 (1995) 233
The HREM use of the FEGTEM for the study of interfaces, *Stobbs, Sato and Stobbs* 58 (1995) 275
Observation of crystal distortions in SiGe/Si superlattice using a new application of large-angle convergent-beam electron diffraction, *Atici and Cherns* 58 (1995) 435
Energy-filtered transmission electron microscopy of Si_mGe_n superlattices and Si–Ge heterostructures. I. Experimental results, *Jäger and Mayer* 59 (1995) 33
Modelling the bonding at metal–ceramic interfaces using PEELS in the STEM, *Brydson, Bruley, Müllejans, Scheu and Rühle* 59 (1995) 81
A quantitative approach for spatially-resolved electron energy-loss spectroscopy of grain boundaries and planar defects on a sub-nanometer scale, *Gu, Čeh, Stemmer, Müllejans and Rühle* 59 (1995) 215
Energy-filtering and composition-sensitive imaging in surface and interface studies using HREM, *Wang and Shapiro* 60 (1995) 115
On the resolution of semiconductor multilayers with a scanning electron microscope, *Merli, Migliori, Nacucchi, Govoni and Mattei* 60 (1995) 229

Microscopic methods, specifically for surfaces

Atomic step imaging on silicon surfaces by scanning electron microscopy, *Homma, Tomita and Hayashi* 52 (1993) 187
Surface electromigration of metal atoms on modified Si(111) surfaces studied by REM, *Yamaguchi, Ohkawa and Yagi* 52 (1993) 306
Kinematic analysis of transmission electron diffraction data from Si(111)-7 × 7, *Twesten and Gibson* 53 (1994) 223
Scanning tunneling microscopic studies of surface reconstructed structures for metal/Si(100) systems, *Ichinokawa, Itoh, Schmid, Winau and Kirschner* 54 (1994) 116
Bloch-wave analysis of periodic surface contrast in zone-axis images, *Goodman, Matheson and Dong* 55 (1994) 314
Surface relaxation of strained heterostructures revealed by Bragg line splitting in LACBED patterns, *Chou, Anderson, Cockayne, Sikorski and Vaughan* 55 (1994) 334
Quantitative surface chemical mapping with Auger and backscattered electron signals, *Prutton, Barkshire and Crone* 59 (1995) 47
Energy-filtering and composition-sensitive imaging in surface and interface studies using HREM, *Wang and Shapiro* 60 (1995) 115

Miscellaneous instruments

Low-energy ion optical system with a liquid-metal ion source for imaging and processing solid structures, *Driesel* 52 (1993) 65
Electron diffraction from gratings fabricated by electron beam nanolithography, *Ito, Bleloch, Paterson and Brown* 52 (1993) 347
Lithium field desorption microscope: a new tool for surface investigations, *Medvedev, Suchorski and Block* 53 (1994) 27

Miscellaneous methods

Dislocation contrast in high-angle hollow-cone dark-field TEM, *Wang* 53 (1994) 73
Dynamic observation of a microelectric field in an oxide superconducting material by electron interference microscopy, *Ogai, Kimura and Shimizu* 54 (1994) 345
The α-fringe contrast of thin twins in relation to the anomalous weak-beam contrast of stacking faults, *Chen and Stobbs* 58 (1995) 289
Nanometric observations at low energy by Fresnel projection microscopy: carbon and polymer fibres, *Vu Thien Binh, Semet and Garcia* 58 (1995) 307
The problem of absorption in the Fresnel fringe analysis, *Schuhrke, Zweck and Hoffmann* 58 (1995) 319
Quantitative mapping of the magnetic induction distribution using Foucault images formed in a transmission electron microscope, *Daykin and Petford-Long* 58 (1995) 365

Miscellaneous theories

Recent studies of short-range order in alloys: the Cowley theory revisited, *Reinhard and Moss* 52 (1993) 223
Effects of crystal surface roughness on X-ray CTR scattering, *Harada* 52 (1993) 233
What the latest diffraction techniques can tell us about an old material: steel, *Butler and Cohen* 52 (1993) 238

Near field optical microscopy (NFOM)

Near-field fluorescent imaging of single proteins, *Dunn, Allen, Joyce, Anderson and Xie* 57 (1995) 113
Measurements of lateral distribution of fluorescence intensities and fluorescence spectra of microareas by a combined SNOM and AFM, *Fujihira, Monobe, Muramatsu and Ataka* 57 (1995) 118

Photon scanning tunneling microscopy of optical channel waveguides, *Choo, Chudgar, Jackson, De Brabander, Kumar and Boyd* 57 (1995) 124
Applications of apertured photon scanning tunnelling microscopy (APSTM), *Tsai, Kovacs and Moskovits* 57 (1995) 130
Scanning near-field optic/atomic-force microscopy, *Muramatsu, Chiba, Ataka, Monobe and Fujihira* 57 (1995) 141
Comparison of different modes of reflection in near-field optical imaging, *Cline and Isaacson* 57 (1995) 147
Analysis of the near field image formation of dielectric gratings, *Chen and Kupka* 57 (1995) 153
Test of various diffraction theories in the near field of phase objects, *Totzeck and Krumbügel* 57 (1995) 160
Low temperature near field spectroscopy and microscopy, *Ghaemi, Cates and Goldberg* 57 (1995) 165
100 femtosecond/100 nanometer near-field probe, *Smith, Orr, Kopelman and Norris* 57 (1995) 173
Near-field optical microscopic recording on Langmuir–Blodgett (LB) films and chemically modified surfaces, *Fujihira, Monobe, Muramatsu and Ataka* 57 (1995) 176
Near-field, far-field and imaging properties of the 2D aperture SNOM, *Novotny, Pohl and Regli* 57 (1995) 180
Analysis of near field tip patterns including object interaction using finite-difference time-domain calculations, *Christensen* 57 (1995) 189
A perturbative diffraction theory of a multilayer system: applications to near-field optical microscopy SNOM and STOM, *Barchiesi and Van Labeke* 57 (1995) 196
Tip optics for illumination NSOM: extended-zone approach, *Yakobson and Paesler* 57 (1995) 204
Photodetector with subwavelength spatial resolution, *Kolb, Obermüller, Karraï, Abstreiter, Böhm, Tränkle and Weimann* 57 (1995) 208
Biological near-field scanning optical microscopy: instrumentation and sample issues for shear-force feedback, *Valaskovic, Holton and Morrison* 57 (1995) 212
Near-field optical microscopy at the liquid/air interface, *Seaver, Duncan and Frost* 57 (1995) 219
A simple technique for screening near-field probes, *Cloninger, Balasubramaniam, Boudreau, Raja and Hocken* 57 (1995) 223
Combined aperture SNOM/PSTM: best of both worlds?, *Hecht, Heinzelmann and Pohl* 57 (1995) 228
Scanning tunnelling optical microscopy – breaking a resolution barrier?, *Williamson, Binks and Miles* 57 (1995) 235
Kinetics, morphology and pulling regimes for sensing tips in near-field microscopy, *Yakobson and Paesler* 57 (1995) 241
Study of the features of PSTM images by means of a perturbative approach, *Sentenac and Greffet* 57 (1995) 246
Numerical analysis of a two-dimensional near-field probe, *Kann, Milster, Froehlich, Ziolkowski and Judkins* 57 (1995) 251
Implementation of an NSOM system for fluorescence microscopy, *Monson, Merritt, Smith, Langmore and Kopelman* 57 (1995) 257
Near field plasmon and force microscopy, *De Hollander, Van Hulst and Kooyman* 57 (1995) 263
Surface polaritons propagation along micropipettes, *Gurevich and Libenson* 57 (1995) 277
Locally resolved infrared spectroscopy, *Piednoir, Creuzet, Licoppe and Ortéga* 57 (1995) 282
Imaging of surface plasmon launch and propagation using a photon scanning tunneling microscope, *Dawson, Smith, De Fornel and Goudonnet* 57 (1995) 287
Contrast mechanisms and imaging modes in near field optical microscopy, *Toledo-Crow, Rogers, Seiferth and Vaez-Iravani* 57 (1995) 293
Optical contrast in near-field techniques, *Moers, Van Hulst, Ruiter and Bölger* 57 (1995) 298
Time as a contrast mechanism in near-field imaging, *LaRosa, Jahncke and Hallen* 57 (1995) 303
Optically trapped non-linear particles as probes for scanning near-field optical microscopy, *Hertz, Malmqvist, Rosengren and Ljungberg* 57 (1995) 309
Scanning probe optical microscopy using a metallic probe tip, *Kawata and Inouye* 57 (1995) 313
Near field optical microscopy using a metallic vibrating tip, *Gleyzes, Boccara and Bachelot* 57 (1995) 318
Electromagnetic fields in two-dimensional models of near-field optical microscope tips, *Castiaux, Dereux, Vigneron, Girard and Martin* 60 (1995) 1

Particle optics

Simulation of a Wien filter as beam separator in a low energy electron microscope, *Tsuno* 55 (1994) 127
Correction of aberrations, a promising means for improving the spatial and energy resolution of energy-filtering electron microscopes, *Rose* 56 (1994) 11

Radiation effects (experimental)

Topics in in-situ experiments in the HVEM, *Mori, Komatsu and Fujita* 51 (1993) 31
HRTEM study of displacement cascade damage in krypton-ion-irradiated silicate – olivine, *Wang, Miller and Ewing* 51 (1993) 339
In situ domain multiplication and migration in the antiferroelectric ceramic PLSnZT, *De Graef, Clarke and Speck* 52 (1993) 179

Electron-beam-induced reduction of Mn^{4+} in manganese oxides as revealed by parallel EELS, *Garvie and Craven* 54 (1994) 83
Electron beam irradiation of natural zeolites at low and room temperatures, *Yokota, Hashimoto and Yamaguchi* 54 (1994) 207
Contrast and radiation damage in point-projection electron imaging of purple membrane at 100 V, *Spence, Qian and Zhang* 55 (1994) 19
UHVEM and AES analysis of electron-irradiation-induced gold-atom implantation into silicon carbide, *Yasuda, Mori and Maeda* 56 (1994) 121
Electron-diffraction channeling effect on defect formation in Si with ⟨110⟩ zone-axis incidence, *Takeda and Horiuchi* 56 (1994) 144
Defect-flow-induced grain boundary migration with segregation under electron irradiation, *Takahashi, Hashimoto and Watanabe* 56 (1994) 193
In situ ion- and electron-irradiation effects studies in transmission electron microscopes, *Allen* 56 (1994) 200
Dual ion beam irradiation system interfaced with a transmission electron microscope and the observation of defect evolution in Ni during irradiation, *Ishikawa and Furuya* 56 (1994) 211
In-situ observations of irradiation-induced phase transformations, *Kinoshita, Tomokiyo and Nakai* 56 (1994) 216
Influence of electron-beam parameters on the radiation-induced formation of graphitic onions, *Lulli, Parisini and Mattei* 60 (1995) 187

Reflection electron microscopy (REM) and reflection high energy electron diffraction (RHEED)

In-situ dynamic processes on cleaved α-alumina bulk crystal surfaces imaged by reflection electron microscopy, *Wang and Bentley* 51 (1993) 64
Surface electromigration of metal atoms on modified Si(111) surfaces studied by REM, *Yamaguchi, Ohkawa and Yagi* 52 (1993) 306
Distorted wave approach to diffuse scattering in THEED and RHEED, *Dudarev, Peng and Whelan* 52 (1993) 393
Observation of planar defects by reflection electron microscopy, *Tsai and Cowley* 52 (1993) 400
Shadow imaging of surface topography in a conventional scanning electron microscope by forward scattered electrons, *Baba-Kishi* 54 (1994) 1
Electron channelling effects at high incident angles in convergent beam reflection high energy electron diffraction, *Wang and Cowley* 55 (1994) 228
The effect of a non-Hermitian crystal potential on the scattering matrix in reflection electron diffraction, *Smith and Josefsson* 55 (1994) 247
Comparison of calculated and experimental convergent-beam RHEED patterns from MgO(100), *Lordi, Ma and Eades* 55 (1994) 284
Reflection electron microscopy of buried interfaces in the transmission geometry, *Spence* 55 (1994) 293
Study of twinning with reflection electron microscopy (REM), *Hsu and Cowley* 55 (1994) 302
The alloying effect of Ag on the reconstruction in Au(111) and (100) surfaces observed by REM, *Uchida, Wang and Zeitler* 55 (1994) 308
Origin of phase shift phenomena in RHEED intensity oscillation curves, *Horio and Ichimiya* 55 (1994) 321
REM in a UHV TEM for the observation of dynamic phase transformation processes on the $Cu_3Au(111)$ surface, *Huang, Gajdardziska-Josifovska and Cowley* 57 (1995) 391
Symmetry analysis of the RHEED patterns from the Si(001)-2 × 1 surfaces, *Ma, Lordi and Eades* 60 (1995) 137

Scanning electron microscopy (SEM)

Atomic step imaging on silicon surfaces by scanning electron microscopy, *Homma, Tomita and Hayashi* 52 (1993) 187
Shadow imaging of surface topography in a conventional scanning electron microscope by forward scattered electrons, *Baba-Kishi* 54 (1994) 1
Deconvolution method to obtain composition profiles from SEM backscattered electron signal profiles for bulk specimens, *Konkol, Wilshaw and Booker* 55 (1994) 183
Field-emission SEM imaging of compositional and doping layer semiconductor superlattices, *Perovic, Castell, Howie, Lavoie, Tiedje and Cole* 58 (1995) 104
Backscattered electron contrast on cross sections of interfaces and multilayers in the scanning electron microscope, *Konkol, Booker and Wilshaw* 58 (1995) 233
Quantitative surface chemical mapping with Auger and backscattered electron signals, *Prutton, Barkshire and Crone* 59 (1995) 47
On the resolution of semiconductor multilayers with a scanning electron microscope, *Merli, Migliori, Nacucchi, Govoni and Mattei* 60 (1995) 229

Scanning transmission electron microscopy (STEM)

Coherence and multiple scattering in "Z-contrast" images, *Treacy and Gibson* 52 (1993) 31
Error analysis of crystalline ptychography in the STEM mode, *McCallum and Rodenburg* 52 (1993) 85
Low-dose thickness measurement of glucose-embedded protein crystals by electron energy loss spectroscopy and STEM dark-field imaging, *Leapman, Brink and Chiu* 52 (1993) 157
Measuring the height of steps on MgO cubes using Fresnel contrast in a scanning transmission electron microscope, *Boothroyd and Humphreys* 52 (1993) 318

Thickness effects in ADF STEM zone axis images, *Hillyard and Silcox* 52 (1993) 325
High-resolution scanning transmission electron microscopy, *Liu and Cowley* 52 (1993) 335
Imaging elastic strains in high-angle annular dark field scanning transmission electron microscopy, *Perovic, Rossouw and Howie* 52 (1993) 353
A versatile, software configurable multichannel STEM detector for angle-resolved imaging, *Haider, Epstein, Jarron and Boulin* 54 (1994) 41
Beyond the conventional information limit: the relevant coherence function, *Nellist and Rodenburg* 54 (1994) 61
Erratum to "Coherence and multiple scattering in 'Z-contrast' images" [Ultramicroscopy 52 (1993) 31–53], *Treacy and Gibson* 54 (1994) 93
Atomic and electronic Z-contrast effects in high-resolution imaging, *Bleloch, Castell, Howie and Walsh* 54 (1994) 107
Theory and computation for imaging in scanning transmission microscopy considering partial coherence in illumination, *Gong* 55 (1994) 373
Instrumental factors in high-resolution FEG STEM, *Von Harrach* 58 (1995) 1
Detector geometry, thermal diffuse scattering and strain effects in ADF STEM imaging, *Hillyard and Silcox* 58 (1995) 6
Imaging modes with an annular detector in STEM, *Cowley, Hansen and Wang* 58 (1995) 18
Far-out-of-focus electron holography in a dedicated FEG STEM, *Mankos, Higgs, Scheinfein and Cowley* 58 (1995) 87
Optimum rotationally symmetric detector configurations for phase-contrast imaging in scanning transmission electron microscopy, *Hammel and Rose* 58 (1995) 403

Scanning tunneling microscopy (STM)

Scanning tunneling microscopic studies of surface reconstructed structures for metal/Si(100) systems, *Ichinokawa, Itoh, Schmid, Winau and Kirschner* 54 (1994) 116
Tip-induced displacement and imaging of a multilayered bacterial structure by scanning tunneling microscopy, *Firtel, Xu, Southam, Mulhern, Blackford, Jericho and Beveridge* 55 (1994) 113
Mechanical interactions in STM imaging of large insulating adsorbates, *Nevernov, Kurnikov and Nicolini* 58 (1995) 269
Reversed metal replicas of freeze-dried proteins to be visualized with the scanning tunneling microscope, *Vélez, Rubio, Agraït, Carrascosa and Vieira* 60 (1995) 41

Specimen preparation and handling

The effect of adsorbate and pretreatment on the shape and reactivity of silica-supported platinum particles, *Ramachandran, Anderson and Datye* 51 (1993) 282
Ultramicrotomy: an alternative cross section preparation for oxidic thin films on glass, *Becker and Bange* 52 (1993) 73
Radiation damage in ion-milled specimens: characteristics, effects and methods of damage limitation, *Barber* 52 (1993) 101
Specific preparation procedures for failure analysis of (sub)micron areas in silicon devices, *Cerva, Huber, Eckers and Mitwalsky* 52 (1993) 127
Positive staining of protein molecules for electron microscopy: polyiodination of the apoferritin shell in ferritin, *Massover* 52 (1993) 383
Direct observation of epitaxially grown C_{60} crystals and molecules on vacuum-deposited MgO films, *Tanaka, Kitagawa, Kachi and Kizuka* 52 (1993) 533
Specimen flatness of glucose-embedded biological materials for electron crystallography is affected significantly by the choice of carbon evaporation stock, *Han, Wolf, Vonck and Glaeser* 55 (1994) 1
A simple preparation method of air-sensitive specimens for transmission electron microscopy demonstrated by Rb_6C_{60}, *Zhang, Zhang, Bernaerts, Van Tendeloo, Amelinckx, Van Landuyt and Werner* 55 (1994) 25
High-resolution electron microscopy of biological specimens in cubic ice, *Cyrklaff and Kühlbrandt* 55 (1994) 141
Analysis of transient structures by cryo-microscopy combined with rapid mixing of spray droplets, *Berriman and Unwin* 56 (1994) 241
A method for 2D crystallization of soluble proteins at liquid–liquid interface, *Aoyama, Ogawa, Kimura and Fujiyoshi* 57 (1995) 345
Artefacts and their healing in ultramicrotomy of side-chain liquid-crystal polymers, *Tournier-Lasserve, Boudet and Sopéna* 58 (1995) 123
Reversed metal replicas of freeze-dried proteins to be visualized with the scanning tunneling microscope, *Vélez, Rubio, Agraït, Carrascosa and Vieira* 60 (1995) 41
Application of the ionless tripod polisher to the preparation of YBCO superconducting multilayer and bulk ceramics thin films, *Ayache and Albarède* 60 (1995) 195
Preparation of TEM plan-view and cross-sectional specimens of ZnSe/GaAs epilayers by chemical thinning and argon ion milling, *Wang and Fung* 60 (1995) 427

Spectrometers

Commercial spectrometer modifications for energy filtering of electron diffraction patterns and images, *Holmestad, Krivanek, Høier, Marthinsen and Spence* 52 (1993) 454
Low energy (< 50 eV) secondary electron separator for nm-scale SE spectroscopy and imaging in STEM, *Tomita and Bleloch* 54 (1994) 125

An imaging filter for high voltage electron microscopy, *Gubbens, Kraus, Krivanek and Mooney* 59 (1995) 255
An imaging filter for biological applications, *Krivanek, Friedman, Gubbens and Kraus* 59 (1995) 267

Spectroscopy in NFOM

Measurements of lateral distribution of fluorescence intensities and fluorescence spectra of microareas by a combined SNOM and AFM, *Fujihira, Monobe, Muramatsu and Ataka* 57 (1995) 118
Low temperature near field spectroscopy and microscopy, *Ghaemi, Cates and Goldberg* 57 (1995) 165
Locally resolved infrared spectroscopy, *Piednoir, Creuzet, Licoppe and Ortéga* 57 (1995) 282

Tip scanning instrument design and characterization

Confocal scanning laser – scanning probe hybrid microscope for biological applications, *Schabert, Knapp, Karrasch, Häring and Engel* 53 (1994) 147
Evaluation of the probing profile of scanning force microscopy tips, *Sheiko, Möller, Reuvekamp and Zandbergen* 53 (1994) 371
Scanning near-field optic/atomic-force microscopy, *Muramatsu, Chiba, Ataka, Monobe and Fujihira* 57 (1995) 141
Comparison of different modes of reflection in near-field optical imaging, *Cline and Isaacson* 57 (1995) 147
Low temperature near field spectroscopy and microscopy, *Ghaemi, Cates and Goldberg* 57 (1995) 165
Characterization of the temporal behavior of ultrashort pulses emerging from a near-field fiber probe, *Dunn and Xie* 57 (1995) 169
100 femtosecond/100 nanometer near-field probe, *Smith, Orr, Kopelman and Norris* 57 (1995) 173
Photodetector with subwavelength spatial resolution, *Kolb, Obermüller, Karraï, Abstreiter, Böhm, Tränkle and Weimann* 57 (1995) 208
Biological near-field scanning optical microscopy: instrumentation and sample issues for shear-force feedback, *Valaskovic, Holton and Morrison* 57 (1995) 212
A simple technique for screening near-field probes, *Cloninger, Balasubramaniam, Boudreau, Raja and Hocken* 57 (1995) 223
Combined aperture SNOM/PSTM: best of both worlds?, *Hecht, Heinzelmann and Pohl* 57 (1995) 228
Kinetics, morphology and pulling regimes for sensing tips in near-field microscopy, *Yakobson and Paesler* 57 (1995) 241
Implementation of an NSOM system for fluorescence microscopy, *Monson, Merritt, Smith, Langmore and Kopelman* 57 (1995) 257
Near-field magneto-optics with polarization sensitive STOM, *Safarov, Kosobukin, Hermann, Lampel, Marlière and Peretti* 57 (1995) 270
Scanning probe optical microscopy using a metallic probe tip, *Kawata and Inouye* 57 (1995) 313
Near field optical microscopy using a metallic vibrating tip, *Gleyzes, Boccara and Bachelot* 57 (1995) 318
Use of a repositionable substrate to acquire and compare distinct atomic force microscope images of a field of microtubules, *Turner, Chang, Brandow, Murphy and Gaber* 58 (1995) 425

Theoretical aspects of NFOM

Analysis of the near field image formation of dielectric gratings, *Chen and Kupka* 57 (1995) 153
Test of various diffraction theories in the near field of phase objects, *Totzeck and Krumbügel* 57 (1995) 160
Near-field, far-field and imaging properties of the 2D aperture SNOM, *Novotny, Pohl and Regli* 57 (1995) 180
Analysis of near field tip patterns including object interaction using finite-difference time-domain calculations, *Christensen* 57 (1995) 189
A perturbative diffraction theory of a multilayer system: applications to near-field optical microscopy SNOM and STOM, *Barchiesi and Van Labeke* 57 (1995) 196
Tip optics for illumination NSOM: extended-zone approach, *Yakobson and Paesler* 57 (1995) 204
Numerical analysis of a two-dimensional near-field probe, *Kann, Milster, Froehlich, Ziolkowski and Judkins* 57 (1995) 251
Electromagnetic fields in two-dimensional models of near-field optical microscope tips, *Castiaux, Dereux, Vigneron, Girard and Martin* 60 (1995) 1

Three-dimensional reconstruction and stereo microscopy

Automatic 3D alignment of projection images of randomly oriented objects, *Farrow and Ottensmeyer* 52 (1993) 141
High-resolution electron crystallography of protein molecules, *Glaeser and Downing* 52 (1993) 478
Three-dimensional reconstruction from random projections: orientational alignment via Radon transforms, *Radermacher* 53 (1994) 121
The ribosome at improved resolution: new techniques for merging and orientation refinement in 3D cryo-electron microscopy of biological particles, *Penczek, Grassucci and Frank* 53 (1994) 251
Stereoscopy by tilted illumination in transmission electron microscopy, *Fan and Ellisman* 55 (1994) 155
3D reconstruction by combining data from sections cut oblique to different unit cell axes, *Winkler and Taylor* 55 (1994) 357
Restoration of high-tilt electron micrographs using a focus series, *Delaney and Belmont* 56 (1994) 319

PHOELIX: a package for semi-automated helical reconstruction, *Whittaker, Carragher and Milligan* 58 (1995) 245
A marker-free alignment method for electron tomography, *Liu, Penczek, McEwen and Frank* 58 (1995) 393
Improved methods for determination of rotational symmetries in macromolecules, *Kocsis, Cerritelli, Trus, Cheng and Steven* 60 (1995) 219
The relevance of dose-fractionation in tomography of radiation-sensitive specimens, *McEwen, Downing and Glaeser* 60 (1995) 357
Double-tilt electron tomography, *Penczek, Marko, Buttle and Frank* 60 (1995) 393

X-ray microanalysis

Quantitative transmission X-ray microanalysis of ionic compounds, *Van Cappellen and Doukhan* 53 (1994) 343
Characterization of an analytical electron microscope with a NiO test specimen, *Egerton and Cheng* 55 (1994) 43
Interaction delocalization in characteristic X-ray emission from light elements, *Allen, Josefsson and Rossouw* 55 (1994) 258
Solving the crystal structure of a submicrometer phase in TEM, *Liu, Eades and Mazumder* 56 (1994) 253
X-ray emission spectrometry of phase separation in Pt–Rh nanoparticles for nitric oxide reduction, *Lyman, Lakis and Stenger, Jr.* 58 (1995) 25
EDS and EELS using a TEM-FEG microscope, *Stadelmann, Leifer and Verdon* 58 (1995) 35
Determination of Cr particle sizes in thin dilute Cr-in-Cu films from measurement statistics, *Klotzkin and Isaacson* 58 (1995) 261
General formulation for ALCHEMI, *Horita, Matsumura and Baba* 58 (1995) 327